



# INFN SoUP 20|21

The 1st INFN School on Underground Physics: Theory & Experiments



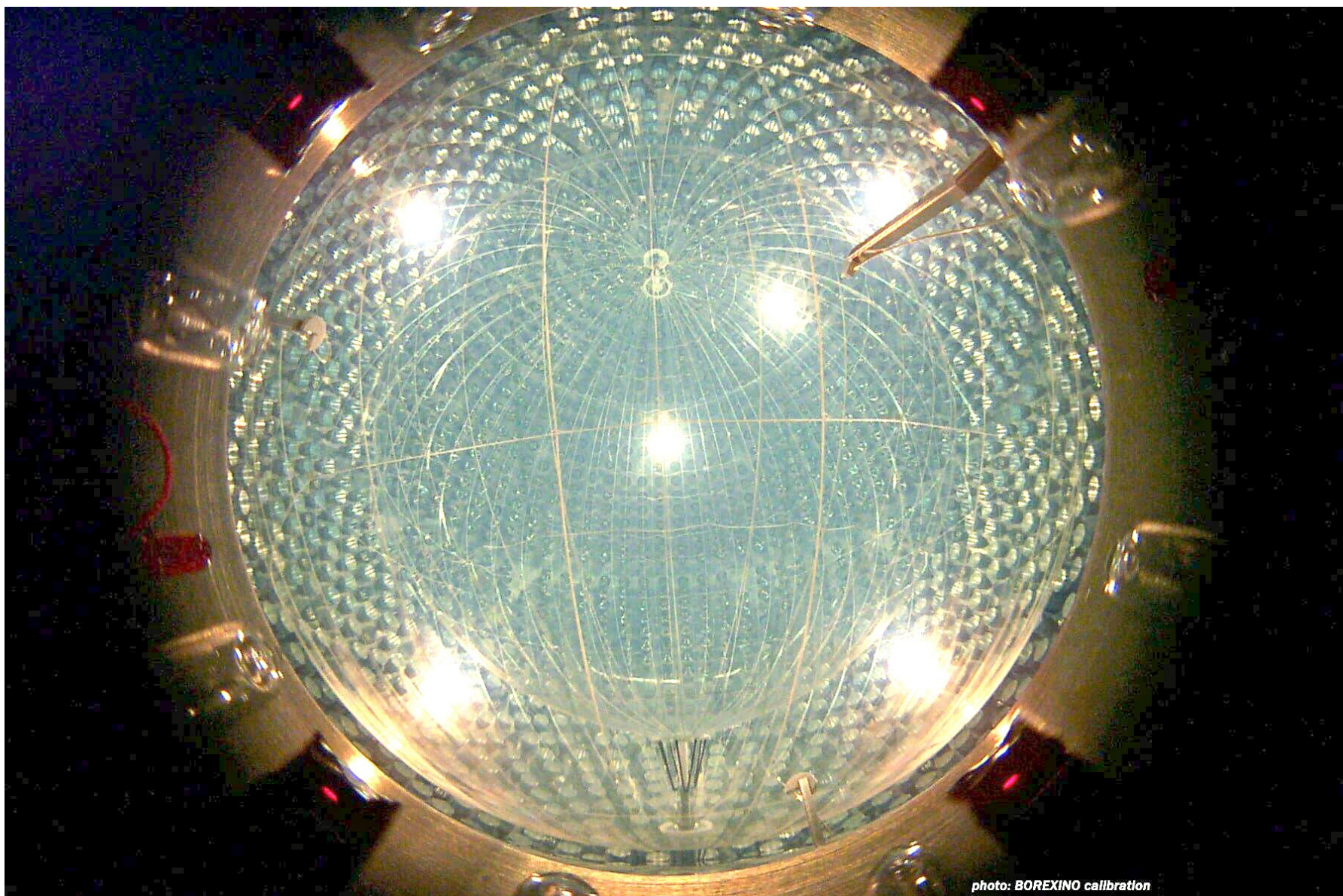


photo: BOREXINO calibration



# Semiconductor Detectors

Alessandro Razeto  
Laboratori Nazionali del Gran Sasso

# References

- Radiation Detection & Measurement – G. Knoll
- Solid State Physics – A. Mermin
  - Chapter 8-9 & 28
- <http://ecee.colorado.edu/~bart/book/book/contents.htm>
  - Chapter 2 & 4
- <http://www.ioffe.ru/SVA/NSM/Semicond/> ← tables of semiconductor properties
- <https://www-physics.lbl.gov/~spieler/>
  - Semiconductor Detector Systems – H. Spieler
- Semiconductor Radiation Detectors – G. Lutz
- [Passage of Particles Through Matter](#)



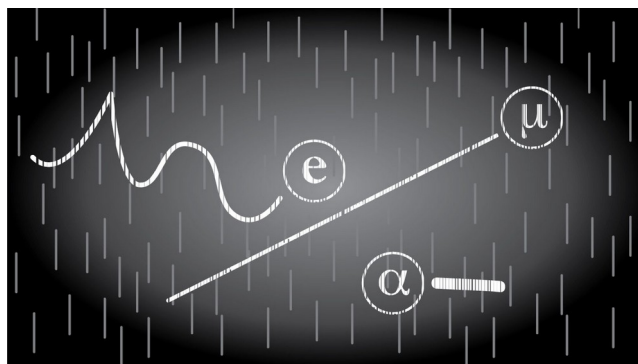
# Detection of physical quantities

- Light
- Particles
- Sound
- Humidity
- Accelerations
- Temperature

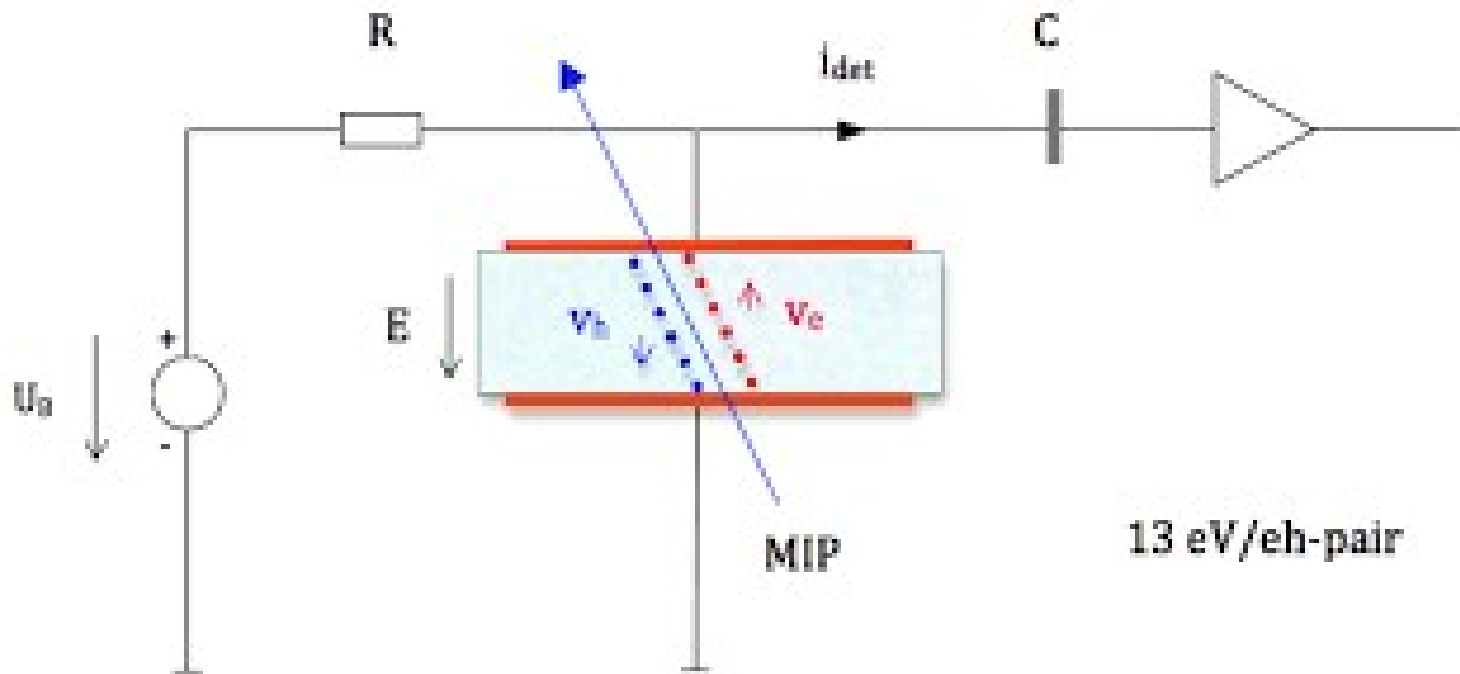


# Detection of physical quantities

- Light
- Particles
- Sound
- Humidity
- Accelerations
- Temperature



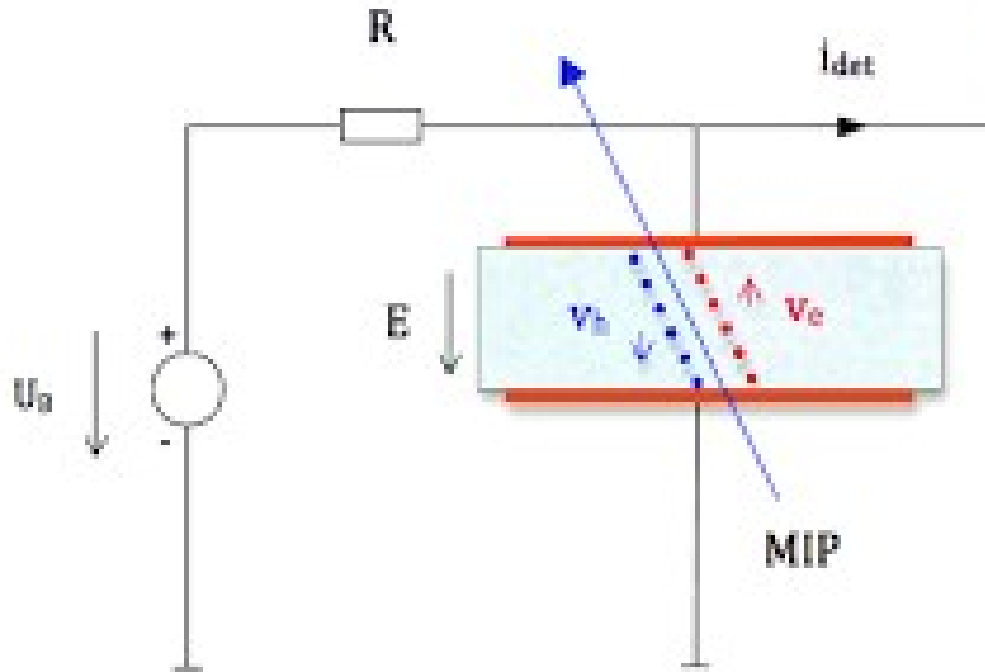
# Base design



13 eV/eh-pair



# Base design

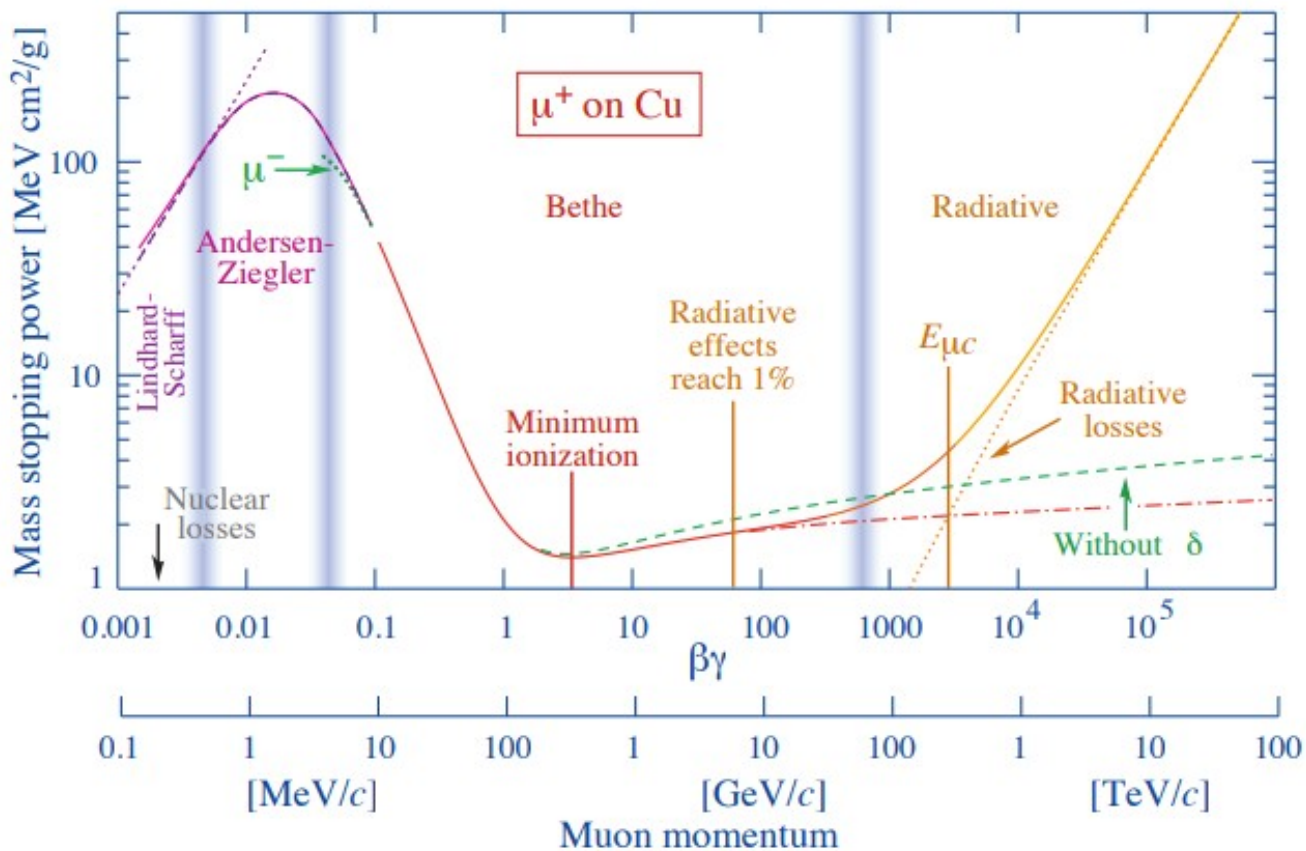


- Non conductive target + field
- A particle releases charge
- The charge is drifted
  - Amplified and acquired
- Leakage is the current with no particle
  - Leakage  $\ll$  signal

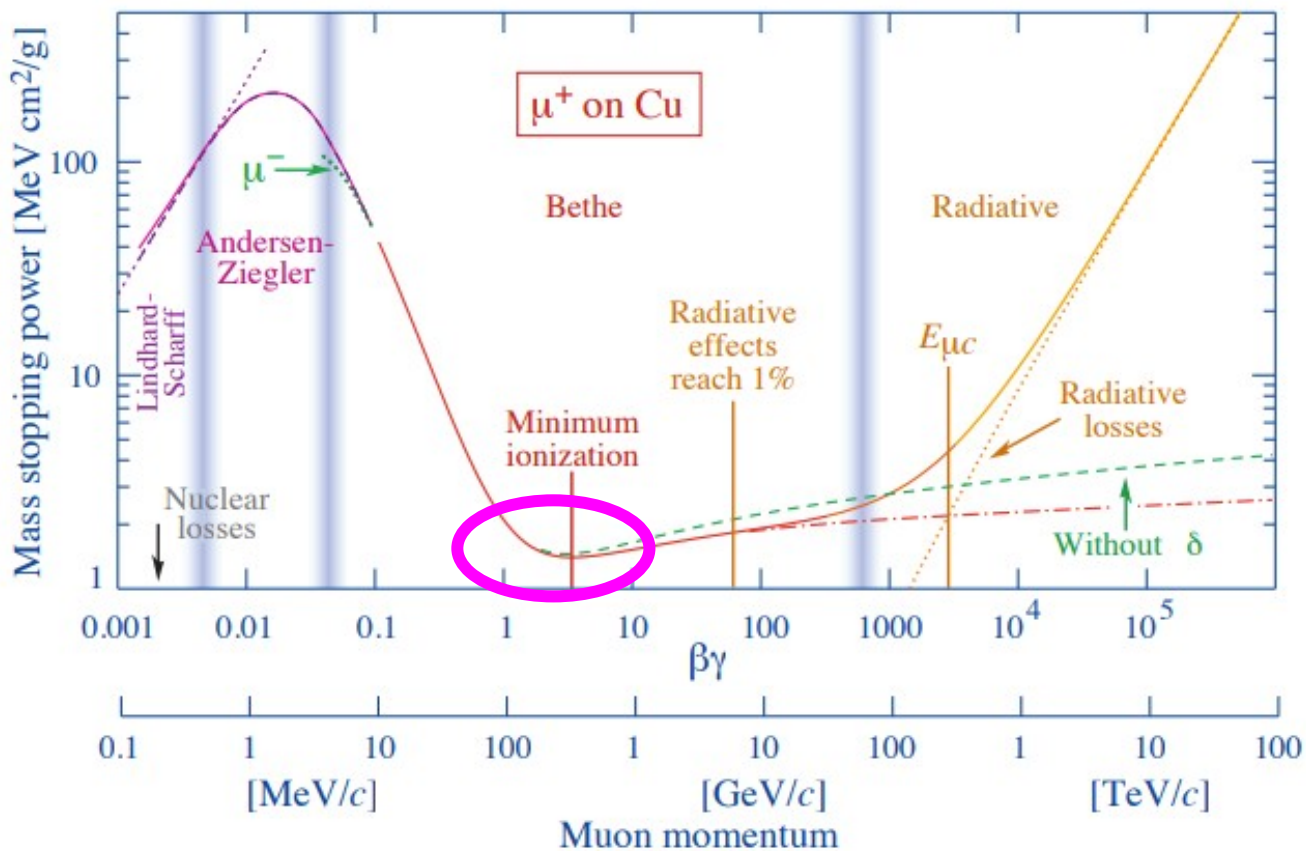




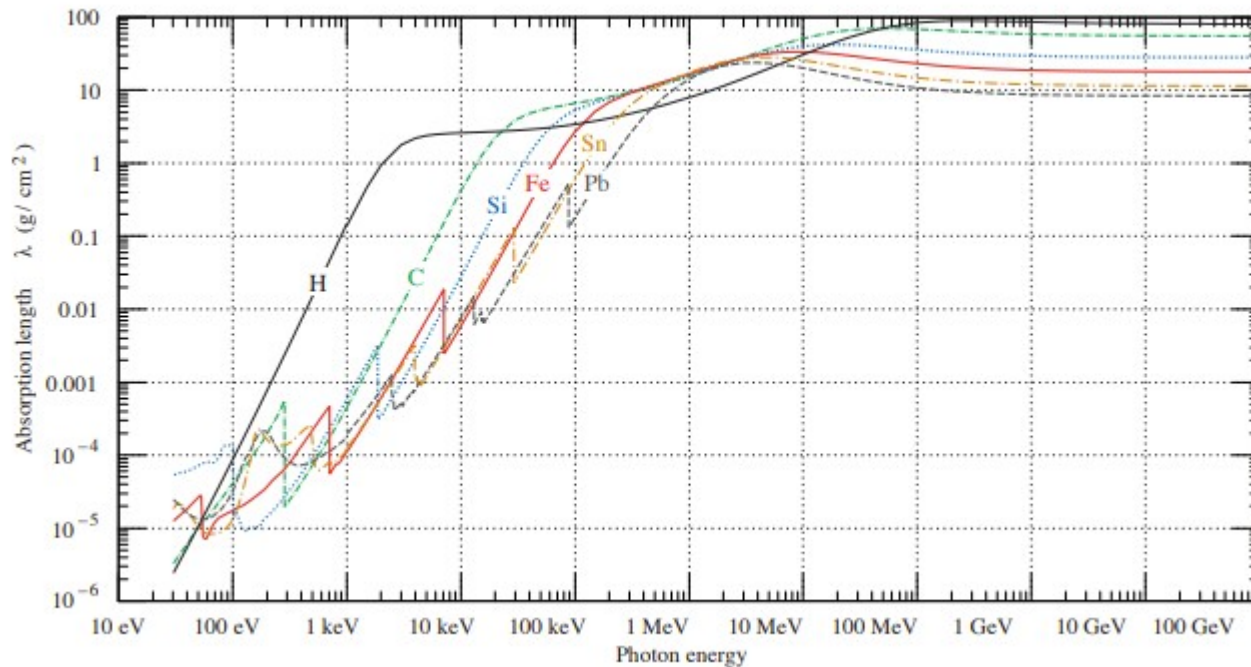
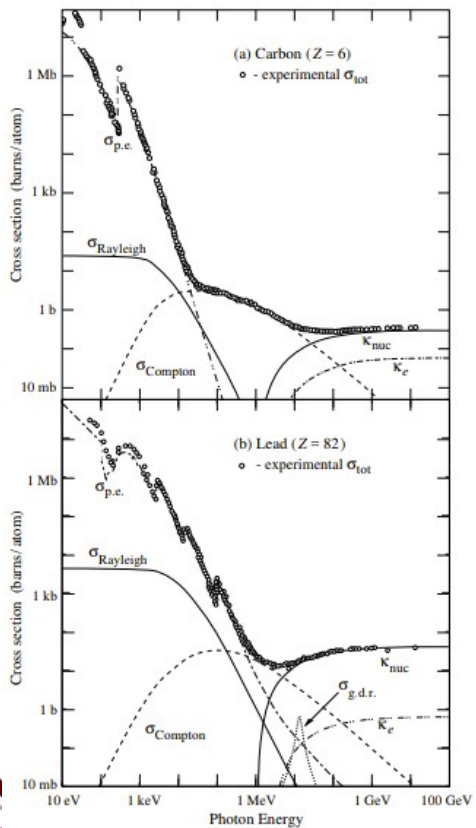
# Interaction with matter



# Interaction with matter



# Photon in matter



# Target

- Non conductive
  - Diamond
  - Selenium
  - Other high purity crystals
  - Silicon & Germanium
- High mobility of carriers
  - High carrier lifetime



# Target

- Non conductive
  - Diamond
  - Selenium
  - Other high purity crystals
  - ~~Silicon & Germanium~~
- High mobility of carriers
  - High carrier lifetime

High resistivity  
10 k $\Omega$ /cm (50  $\Omega$ /cm)



# Target

- Non conductive
  - Diamond
  - Selenium
  - Other high purity crystals
  - ~~Silicon & Germanium~~
- High mobility of carriers
  - High carrier lifetime

Sat. velocity: 10 cm/ $\mu$ s  
Lifetime: few ns  
→ thickness sub-mm



# Target

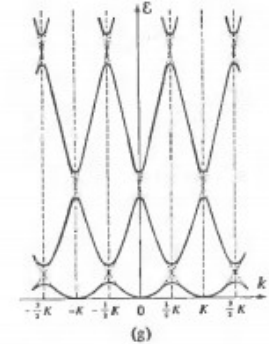
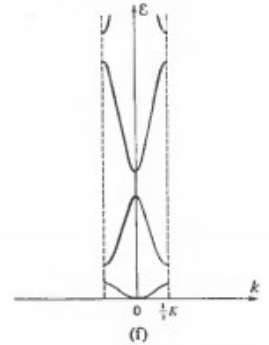
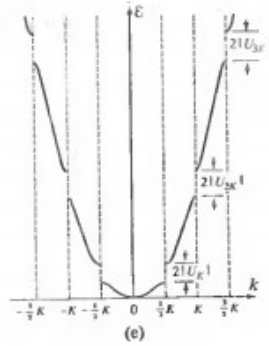
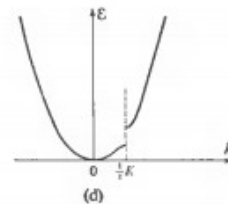
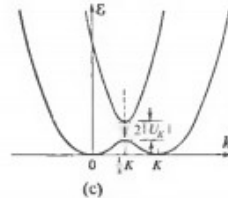
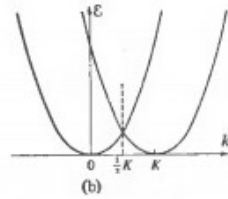
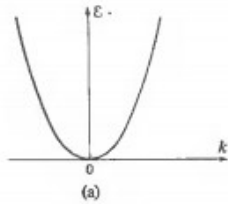
- Non conductive
  - Diamond
  - Selenium
  - Other high purity crystals
  - ~~Silicon & Germanium~~
- High mobility of carriers
  - High carrier lifetime

Sat. velocity: 10 cm/ $\mu$ s  
Lifetime: few ns  
→ thickness sub-mm

Sat. velocity: 1 cm/ $\mu$ s  
Lifetime: few  $\mu$ s  
→ thickness sub-cm



# Band structure

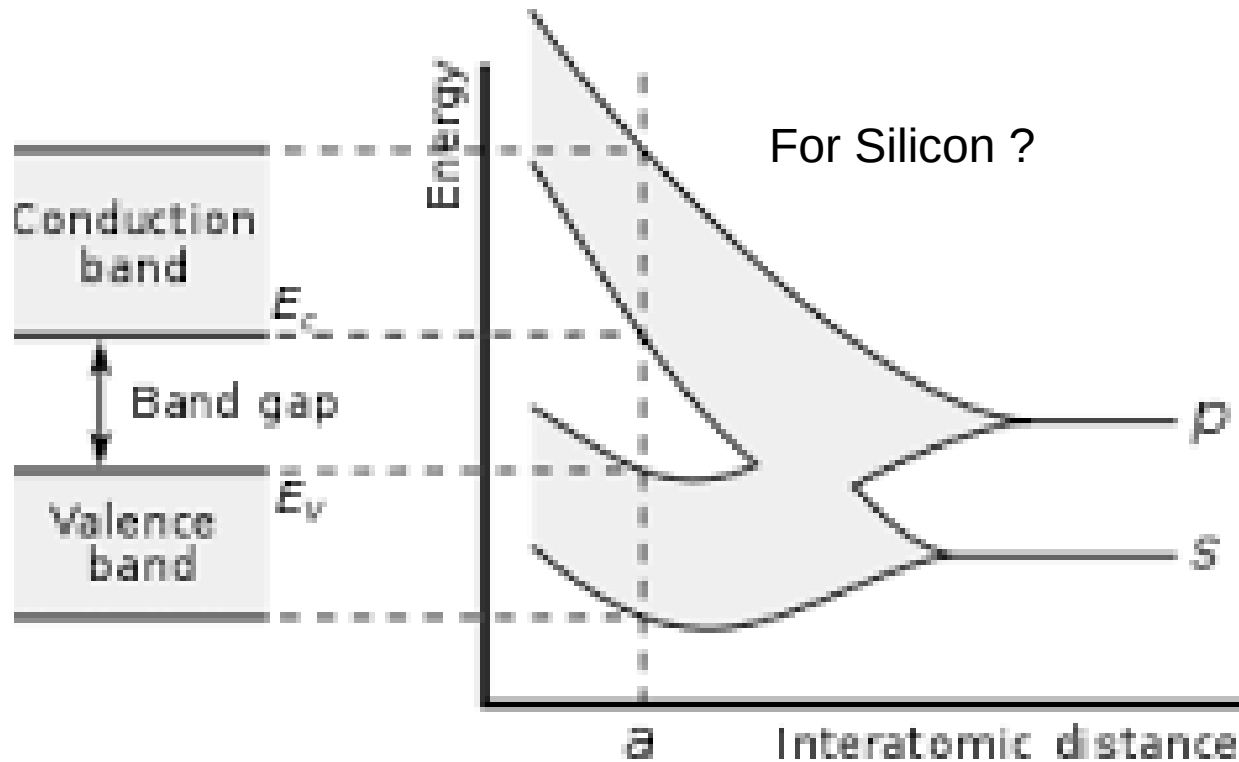


- Simple model with atoms connected by springs
- Periodicity implies the band structure

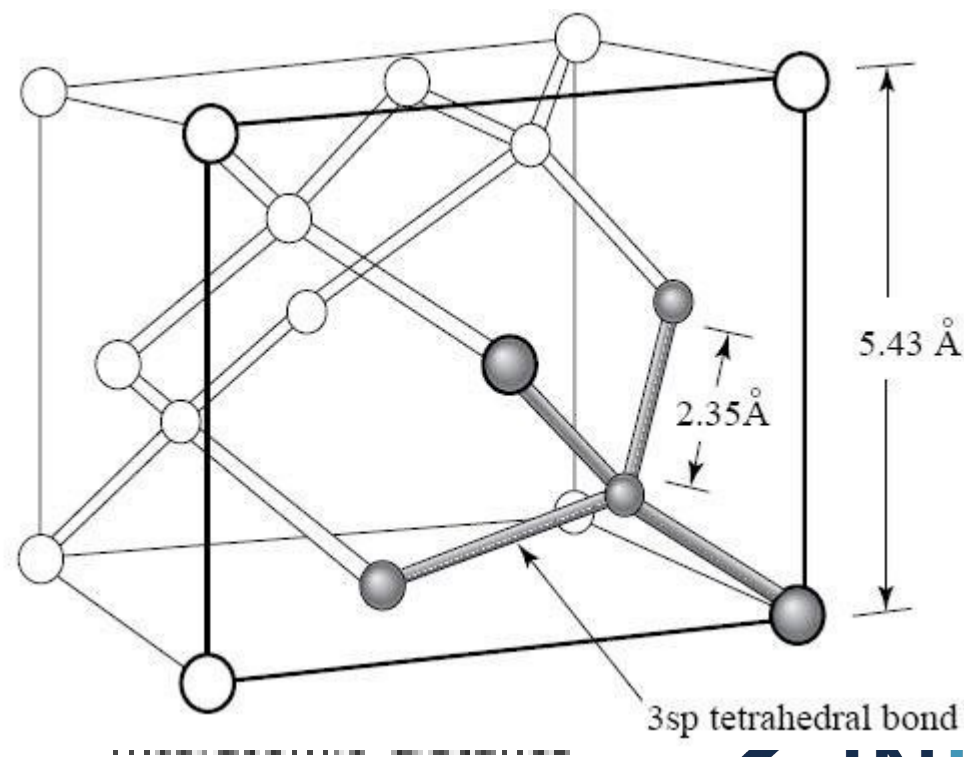
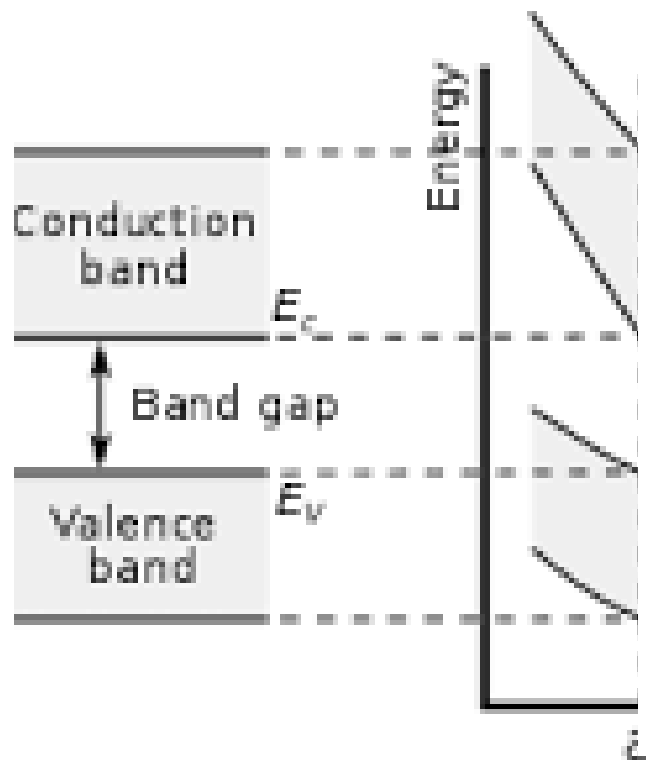




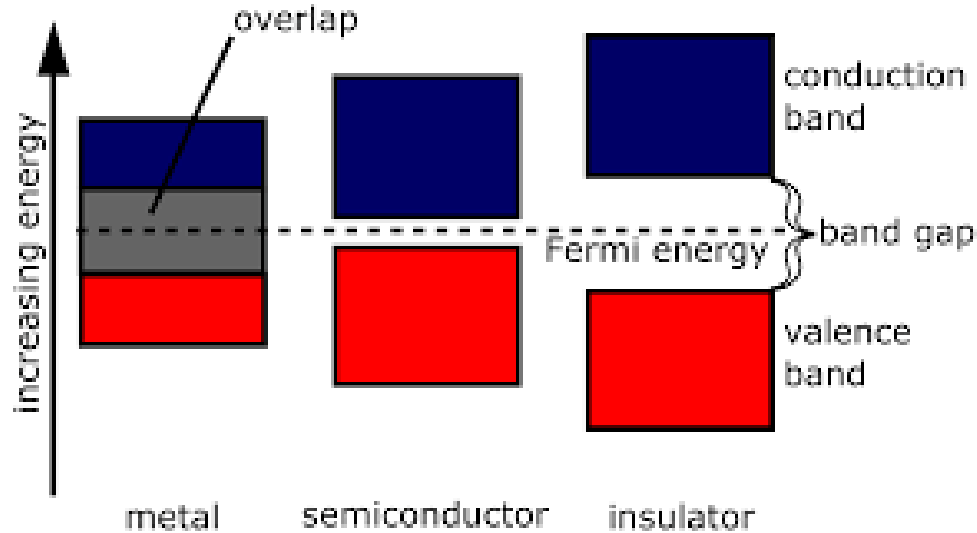
# Band structure



# Band structure

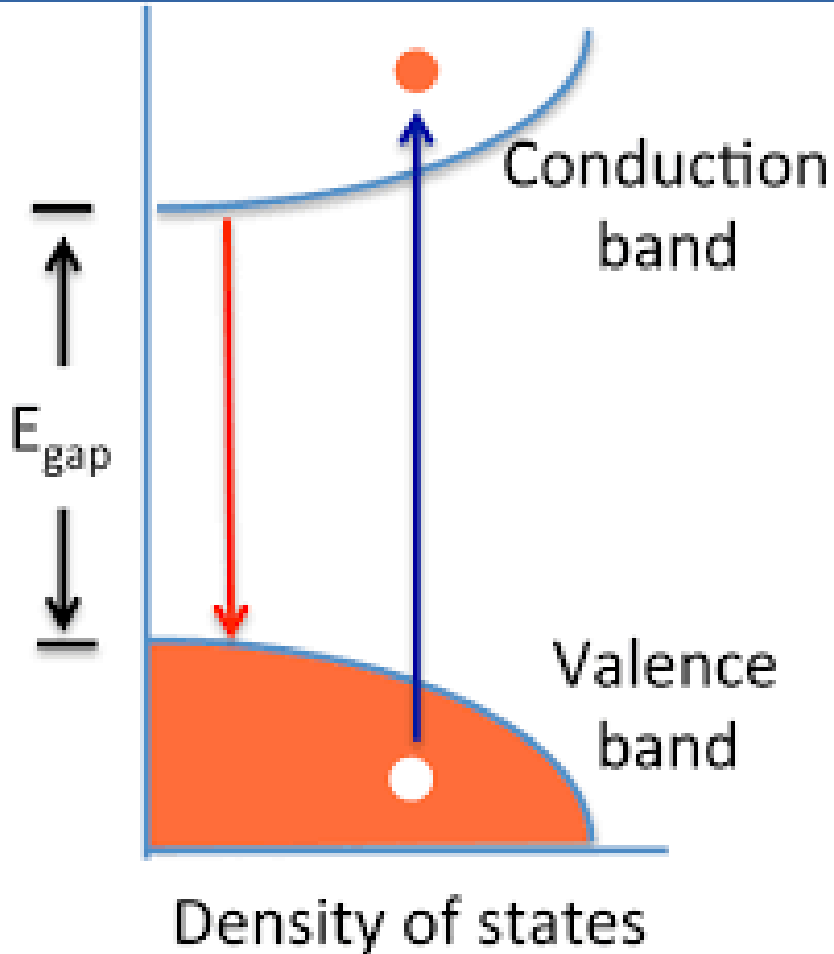


# Semiconductors



- The band gap has to be compared with the  $k_B T$ 
  - 1/40 eV at 300 K
  - Si 1.1 eV
  - Ge 0.6 eV
  - Diamond 5.5 eV
- Typ. the band-gap  $\propto -T$ 
  - Increasing lattice spacing

# Carriers for semi-conductors



- At  $T \ll E_g/k_B$  all electrons are in the valence band
  - No conduction at all
- For  $T < E_g/k_B$  electrons can jump to the conduction band
  - Creating a hole in the valence band ← hole
- For intrinsic semiconductors  $n_h = n_e := n_i$

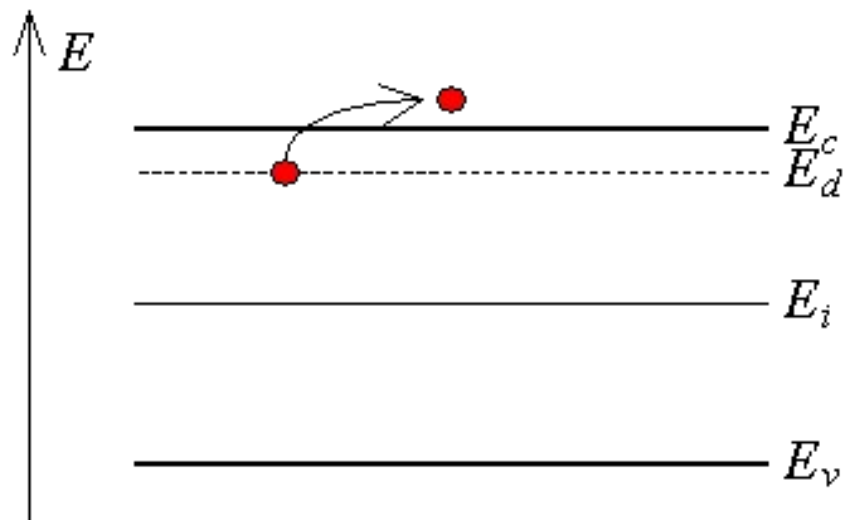
# Carriers for semiconductors

$$n_i(T) = \frac{1}{4} \left( \frac{2k_B T}{\pi \hbar^2} \right)^{3/2} (m_c m_v)^{3/4} e^{-E_g/2k_B T} \quad \text{For intrinsic semiconductors}$$
$$= 2.5 \left( \frac{m_c}{m} \right)^{3/4} \left( \frac{m_v}{m} \right)^{3/4} \left( \frac{T}{300 \text{ K}} \right)^{3/2} e^{-E_g/2k_B T} \times 10^{19} / \text{cm}^3.$$

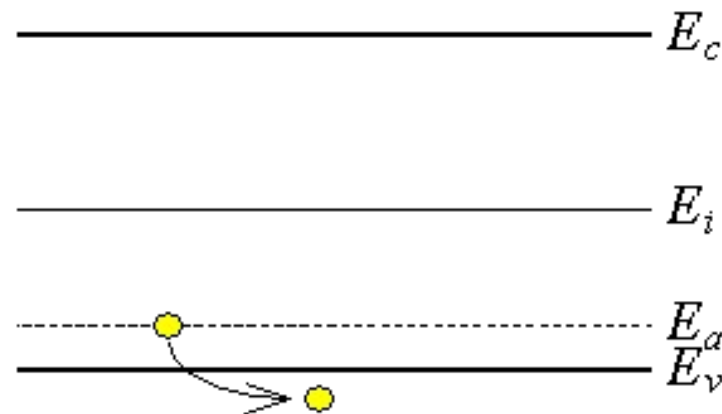
For Si  $\sim 10^{10} / \text{cm}^3$   
For Ge  $\sim 10^{13} / \text{cm}^3$

$$n_c p_v = N_c P_v e^{-(\epsilon_c - \epsilon_v)/k_B T}$$
$$= N_c P_v e^{-E_g/k_B T}.$$

# Dopants



(a)



(b)

# Dopants

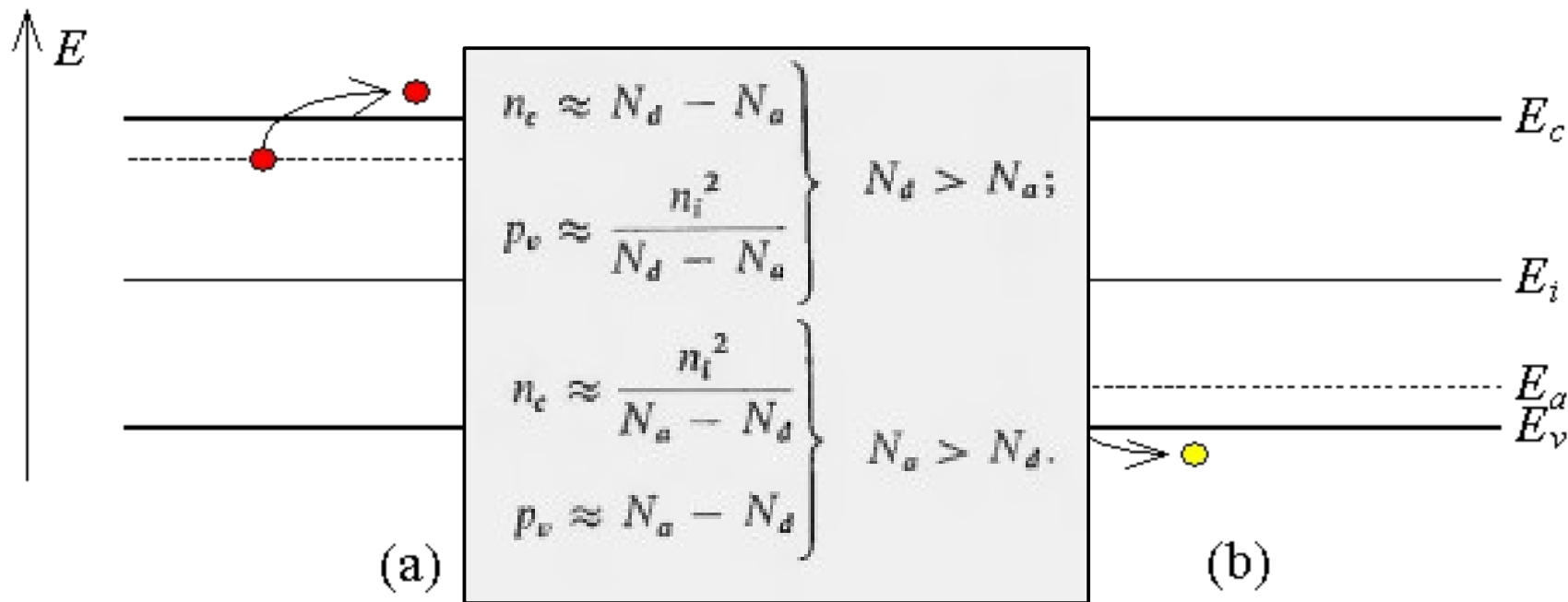
$E$

GROUP III ACCEPTORS (TABLE ENTRY IS $\epsilon_g - \epsilon_v$ )					
	B	Al	Ga	In	Tl
Si	0.046 eV	0.057	0.065	0.16	0.26
Ge	0.0104	0.0102	0.0108	0.0112	0.01
GROUP V DONORS (TABLE ENTRY IS $\epsilon_c - \epsilon_d$ )					
	P	As	Sb	Bi	
Si	0.044 eV	0.049	0.039	0.069	
Ge	0.0120	0.0127	0.0096	—	
ROOM TEMPERATURE ENERGY GAPS ( $E_g = \epsilon_c - \epsilon_v$ )					
Si	1.12 eV				
Ge	0.67 eV				

$E_c$   
 $E_i$   
 $E_d$   
 $E_v$

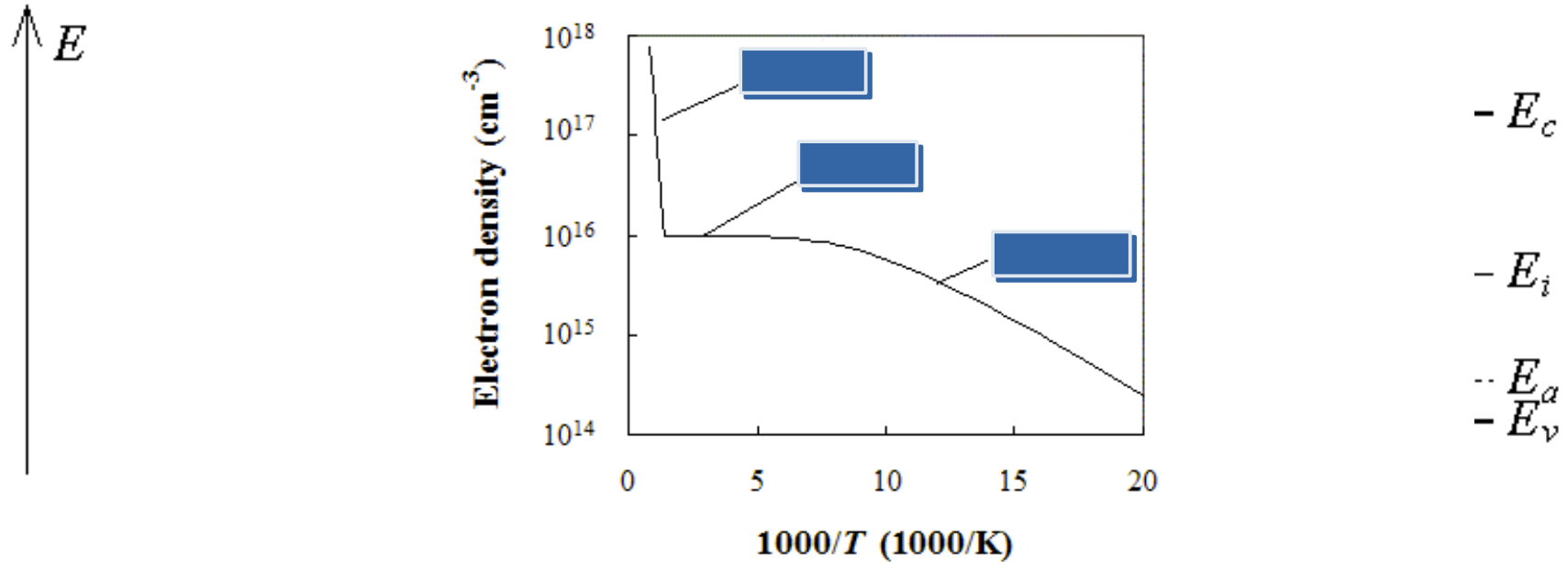


# Dopants





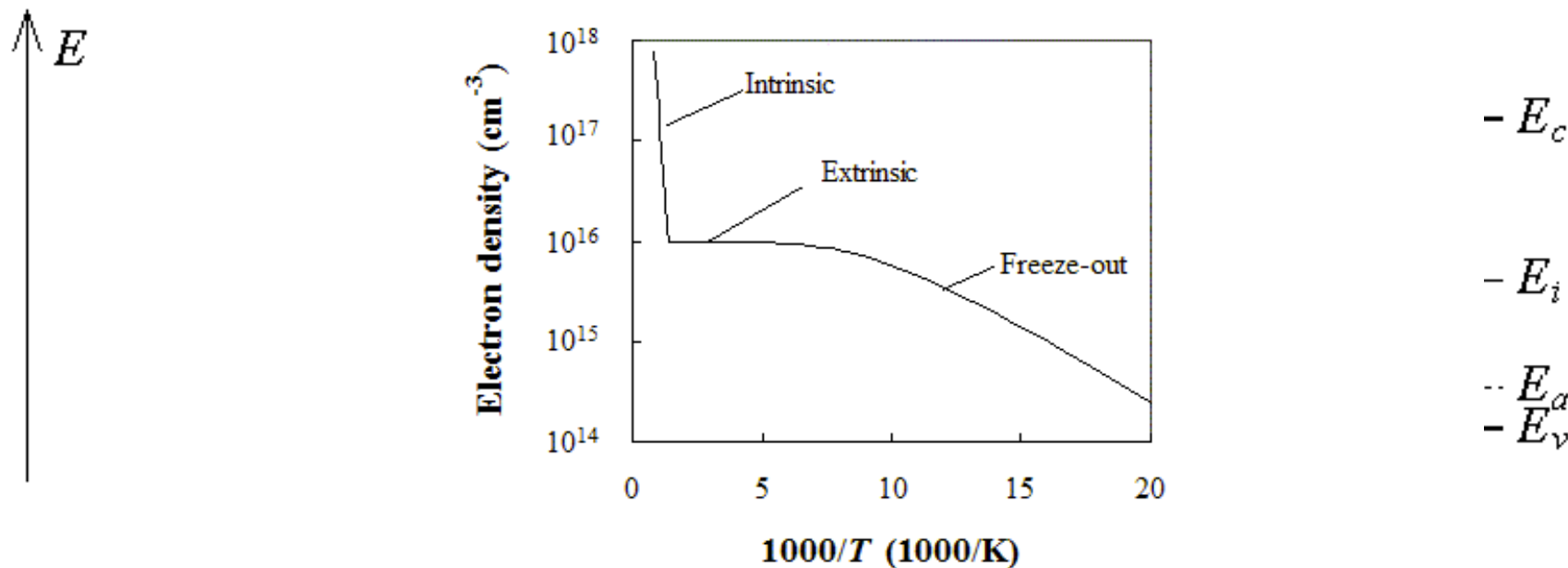
# Dopants




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Figure 2.6.9: Electron density and Fermi energy as a function of temperature in silicon with  $N_d = 10^{16} \text{ cm}^{-3}$ ,  $N_a = 10^{14} \text{ cm}^{-3}$  and  $E_c - E_d = E_a - E_v = 50 \text{ meV}$ . The activation energy at 70 K equals 27.4 meV. 📄

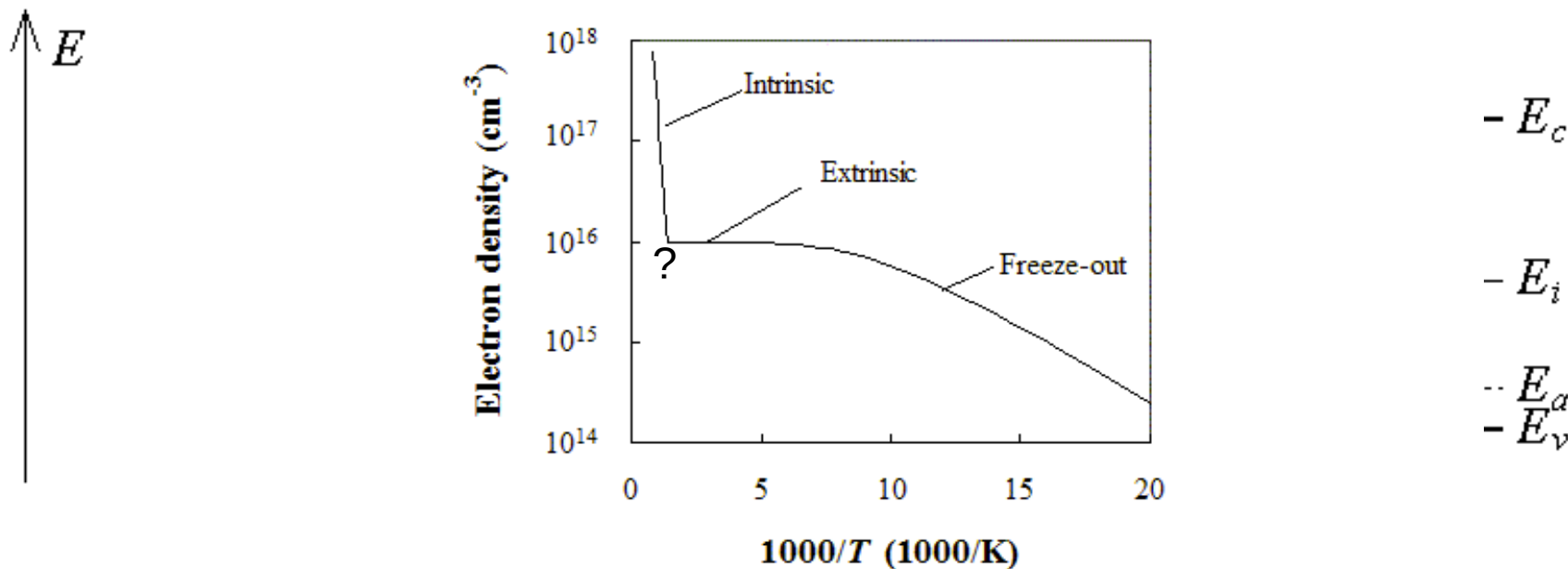
# Dopants



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Figure 2.6.9: Electron density and Fermi energy as a function of temperature in silicon with  $N_d = 10^{16} \text{ cm}^{-3}$ ,  $N_a = 10^{14} \text{ cm}^{-3}$  and  $E_c - E_d = E_a - E_v = 50 \text{ meV}$ . The activation energy at 70 K equals 27.4 meV. 

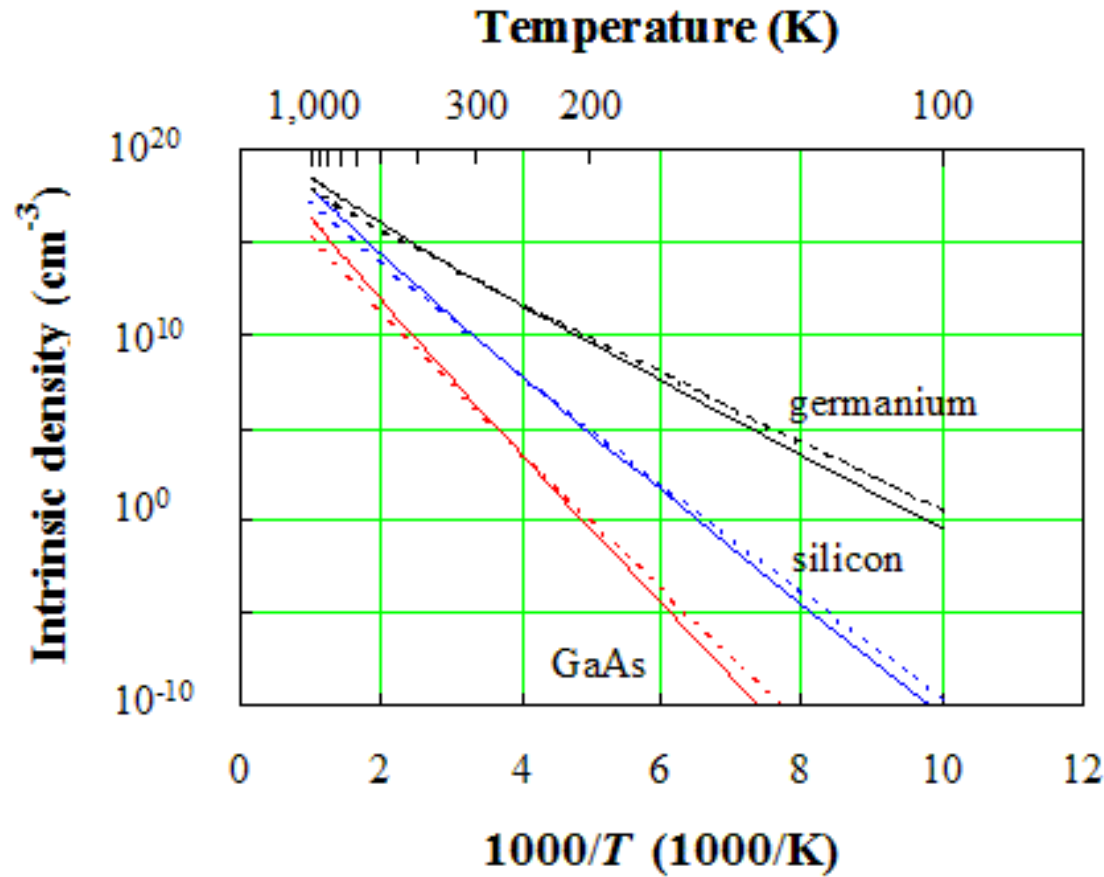
# Dopants



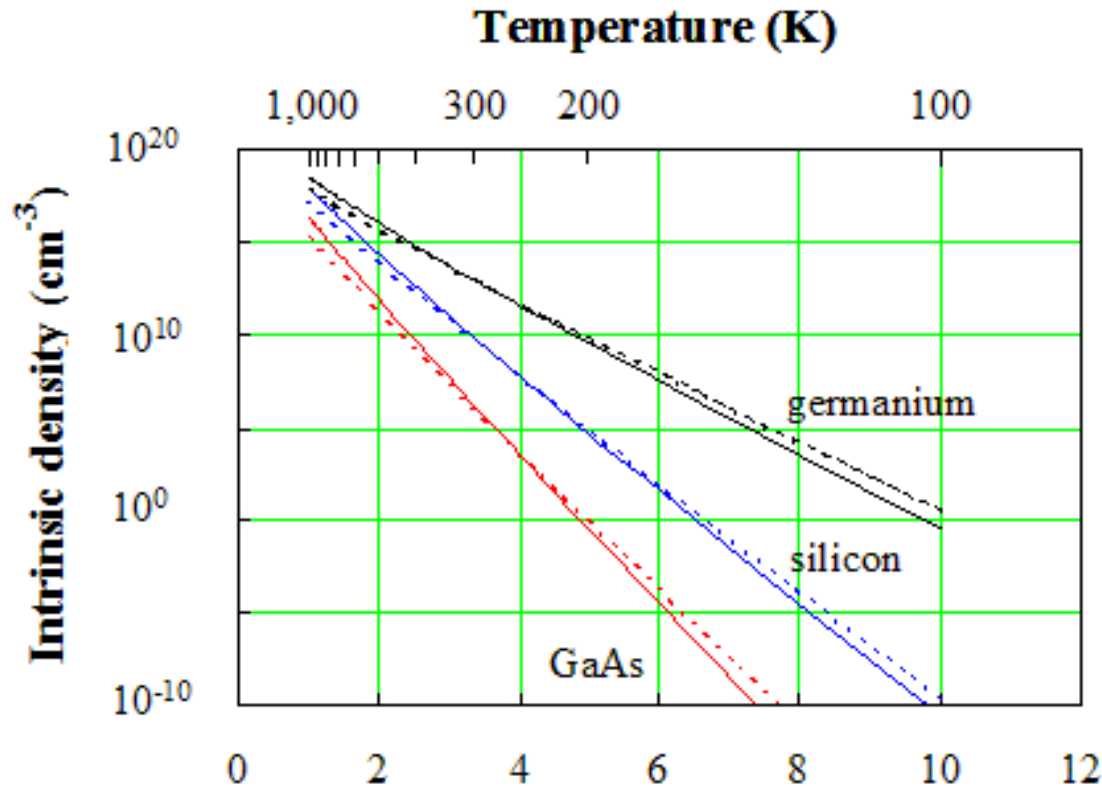
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**Figure 2.6.9:** Electron density and Fermi energy as a function of temperature in silicon with  $N_d = 10^{16} \text{ cm}^{-3}$ ,  $N_a = 10^{14} \text{ cm}^{-3}$  and  $E_c - E_d = E_a - E_v = 50 \text{ meV}$ . The activation energy at 70 K equals 27.4 meV. 📄

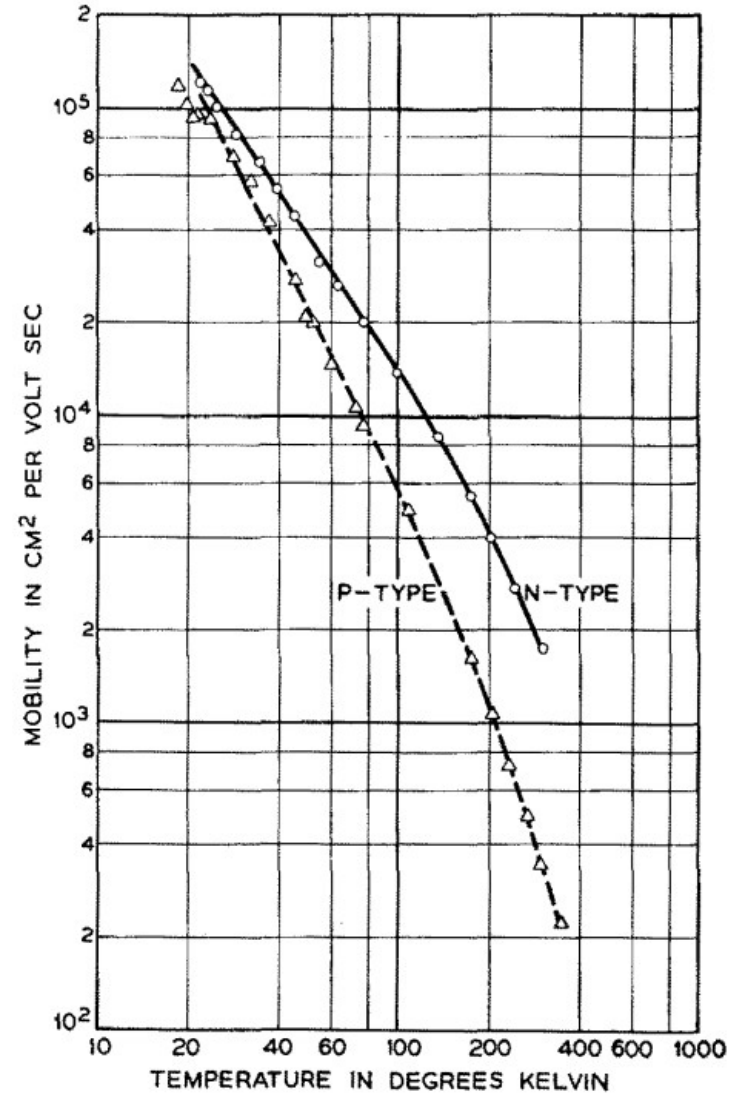


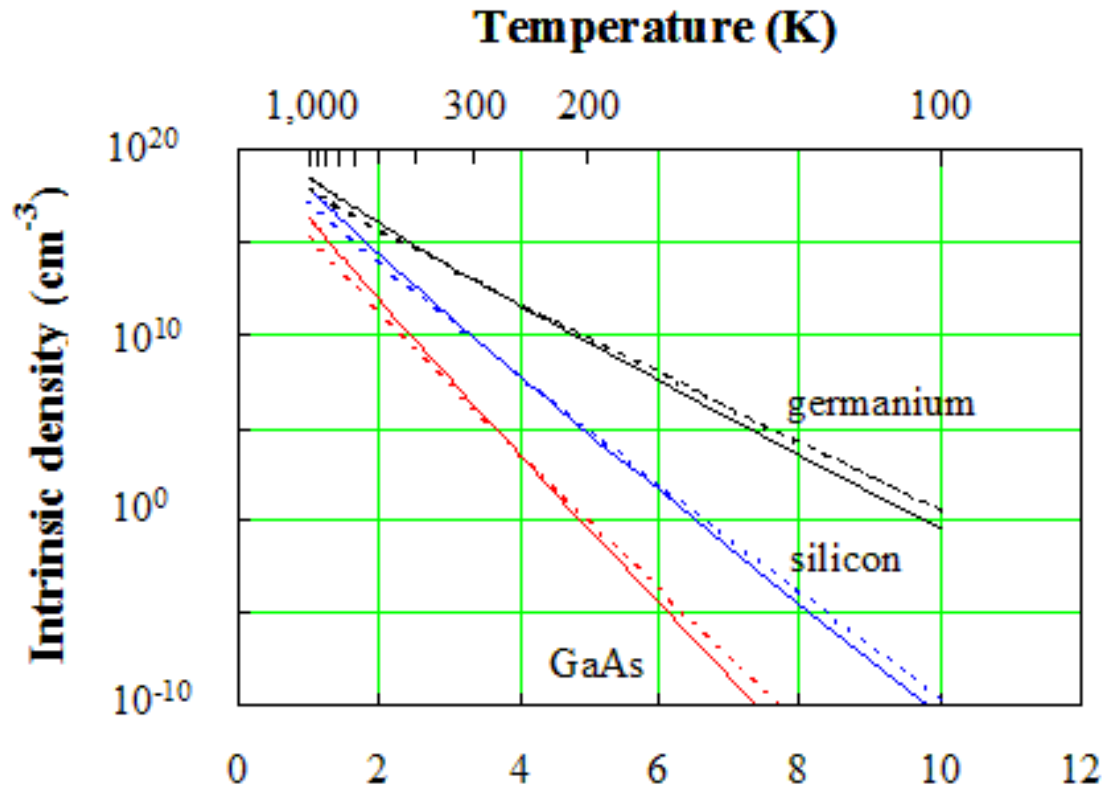


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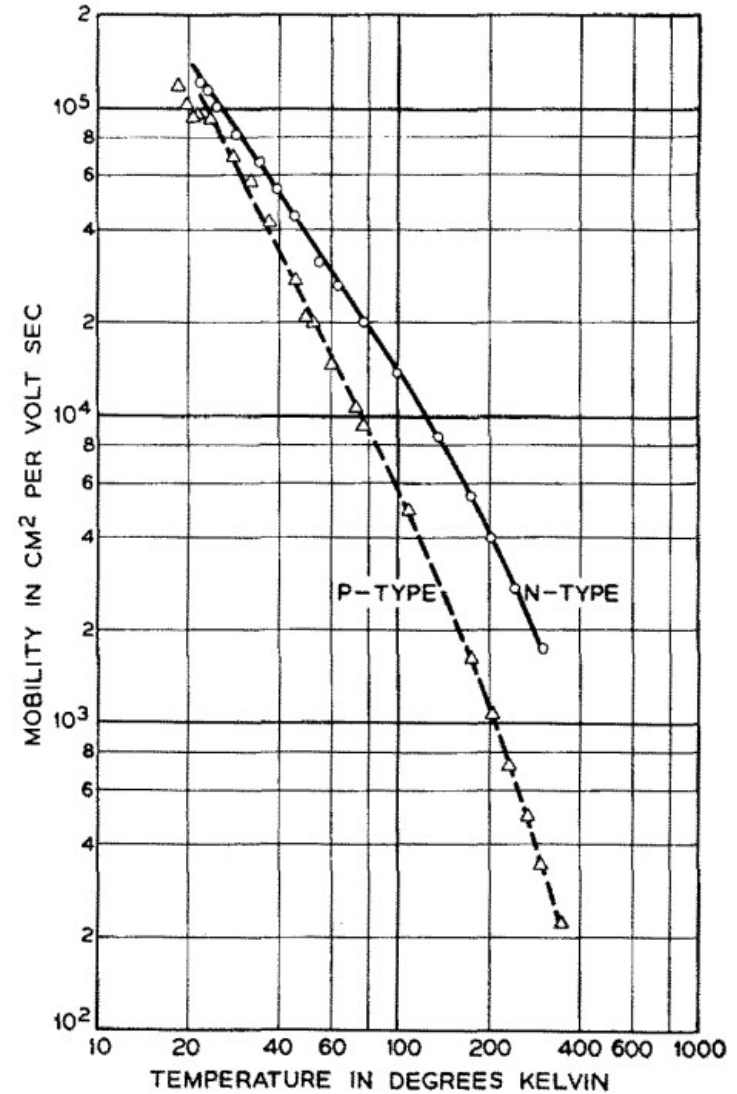


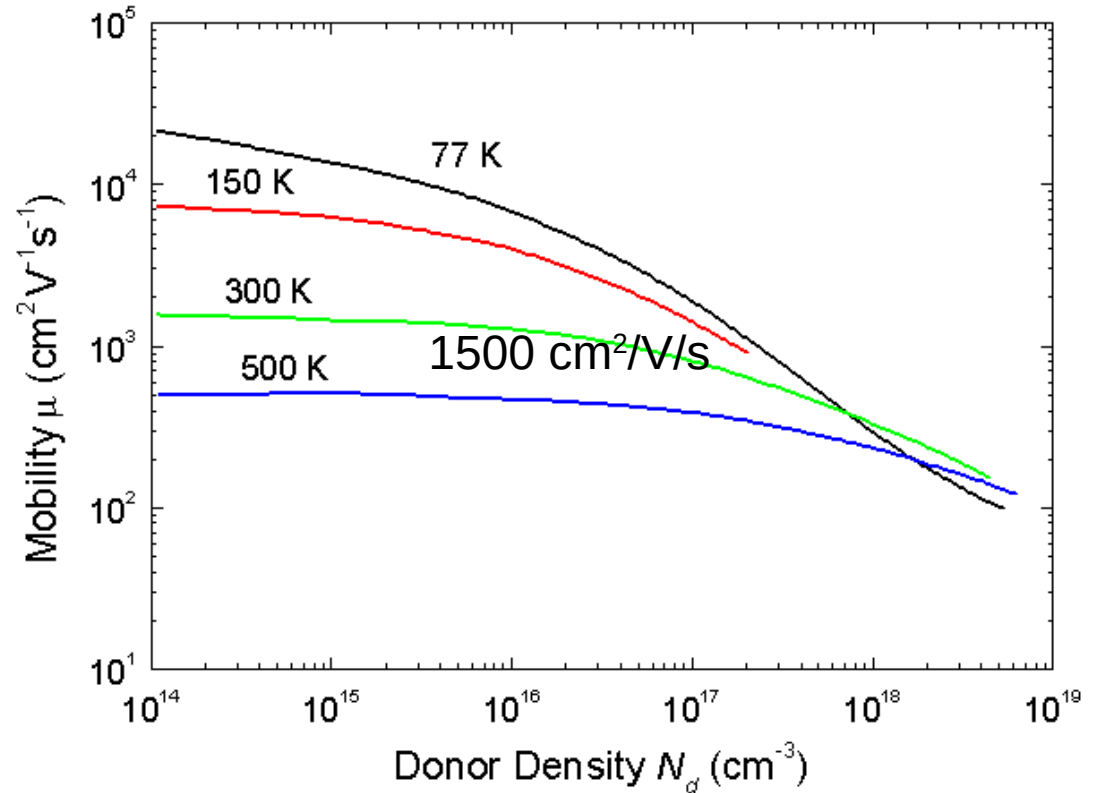
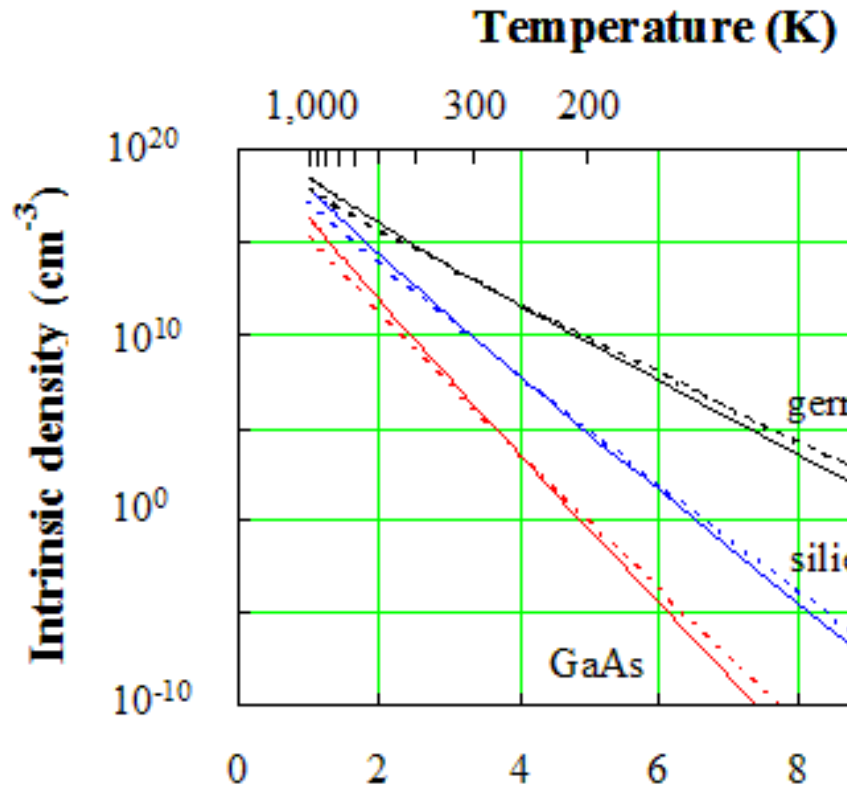
$R = 1/(e \cdot \mu \cdot N_i) \rightarrow$  For Si ?



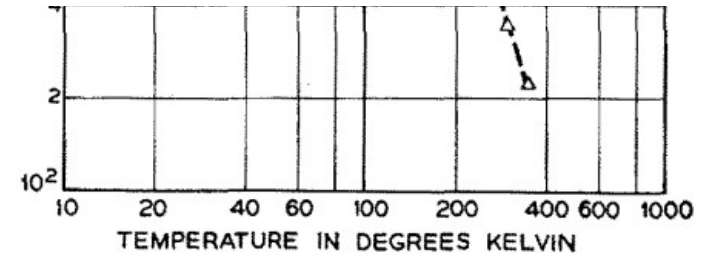








$R = 1/(e \cdot \mu \cdot N_i) \rightarrow$  For Si  $\frac{1}{2} \text{ M}\Omega/\text{cm}$   
 commercially available Si  $\sim 10 \text{ k}\Omega/\text{cm}$





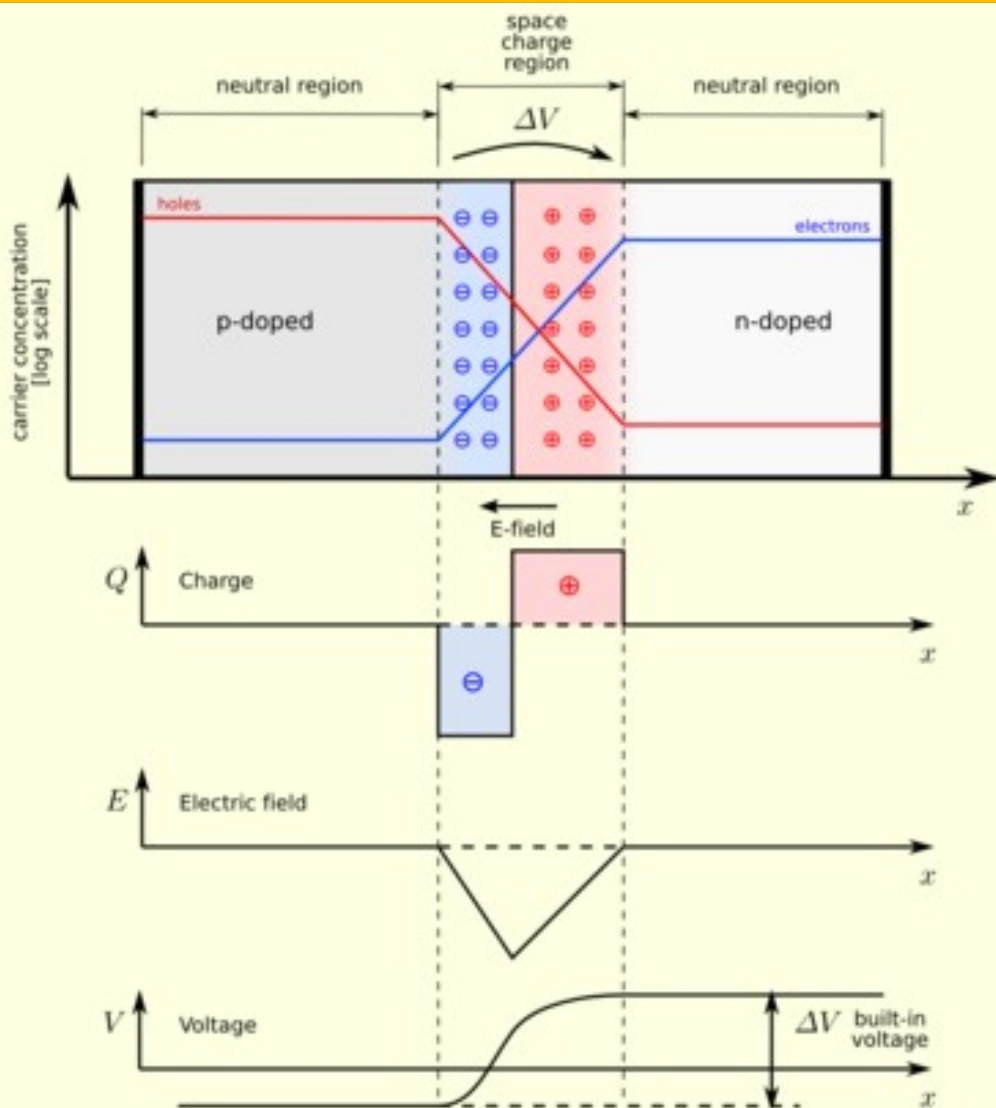
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 commercially available Si  $\sim 10 \text{ k}\Omega/\text{cm}$



Qty	ID	Diam	Type	Dopant	Orien	Res (Ohm-cm)	Thick (um)	Polish	Grade	Lead Time	Quantity	1 Unit Price	5 Unit Price	10 Unit Price	25 Unit Price	50 Unit Price	100 Unit Price
25 	2313	25.4mm	Undoped	Undoped	<111>	>2000	280um	SSP	Test	In Stock	152	\$45.90	\$25.90	\$17.90	\$16.90		
100 	2018	50.8mm	Undoped	Undoped	<100>	>10000	280um	DSP	Prime	In Stock	974	\$59.50	\$39.90	\$32.90	\$23.90	\$22.90	\$20.90
82 	3635	50.8mm	Undoped	Undoped	<100>	>10,000	280um	SSP	Prime	In Stock	82	\$54.90	\$36.90	\$30.90	\$21.90	\$21.90	
20 	3678	50.8mm	Undoped	Undoped	<100>	>5000	500um	SSP	Test	In Stock	20	\$39.90	\$29.90	\$22.90	\$19.9	\$18.90	
100 	3685	76.2mm	Undoped	Undoped	<100>	>10,000	380um	SSP	Prime	5 WEEKS	100		\$49.90	\$39.90	\$29.90	\$27.90	\$26.90
1 	3696	76.2mm	Undoped	Undoped	<100>	>10000	380um	DSP	Prime	In Stock	1	\$65.90	\$55.90	\$45.90	\$38.9		
131 	3193	100mm	Undoped	Undoped	<100>	>10,000	525um	DSP	Prime	In Stock	131	\$145.90	\$99.90	\$79.90	\$65.9	\$61.90	\$59.90
100 	3328	100mm	Undoped	Undoped	<100>	>20,000	525um	SSP	Prime	In Stock	505	\$110.90	\$92.90	\$77.90	\$68.9	\$66.90	\$61.90







- Majority carriers diffusing on the other side of the junction recombine

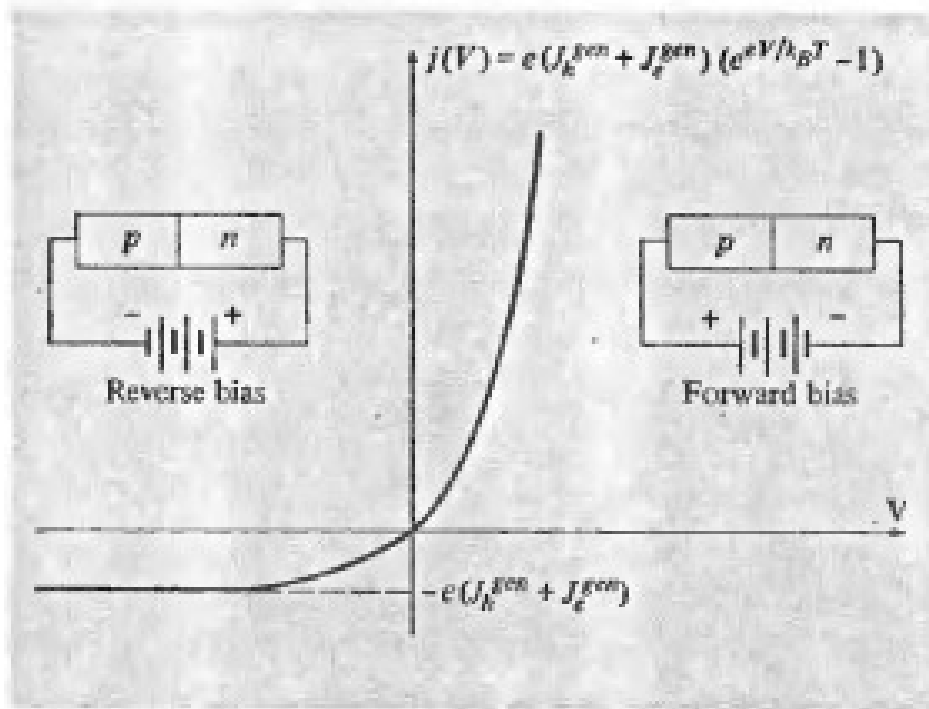
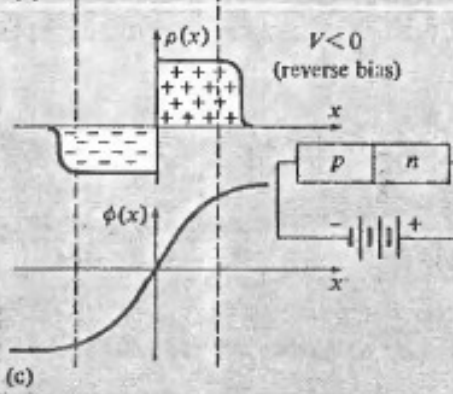
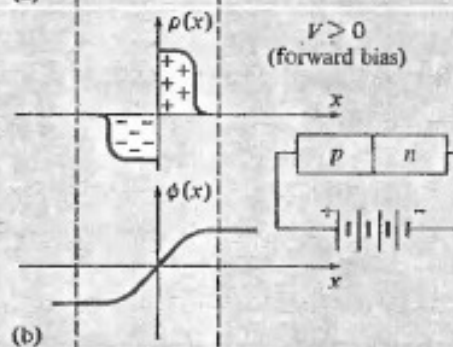
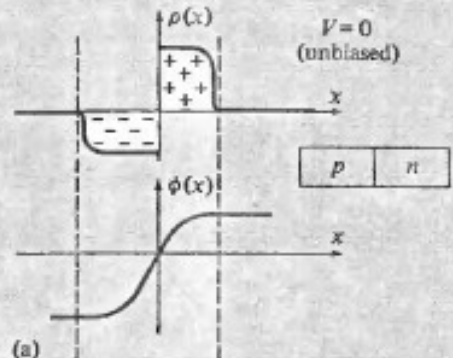
- Depletion layer

- Capacitance

$$C_j = \epsilon A \left[ \frac{q}{2\epsilon(V_0 - V)} \frac{N_d N_a}{N_d + N_a} \right]^{1/2} = \frac{\epsilon A}{W}$$

- $V = k_B T / e \ln \left( \frac{n_a n_d}{n_i^2} \right)$

# Shockley equation

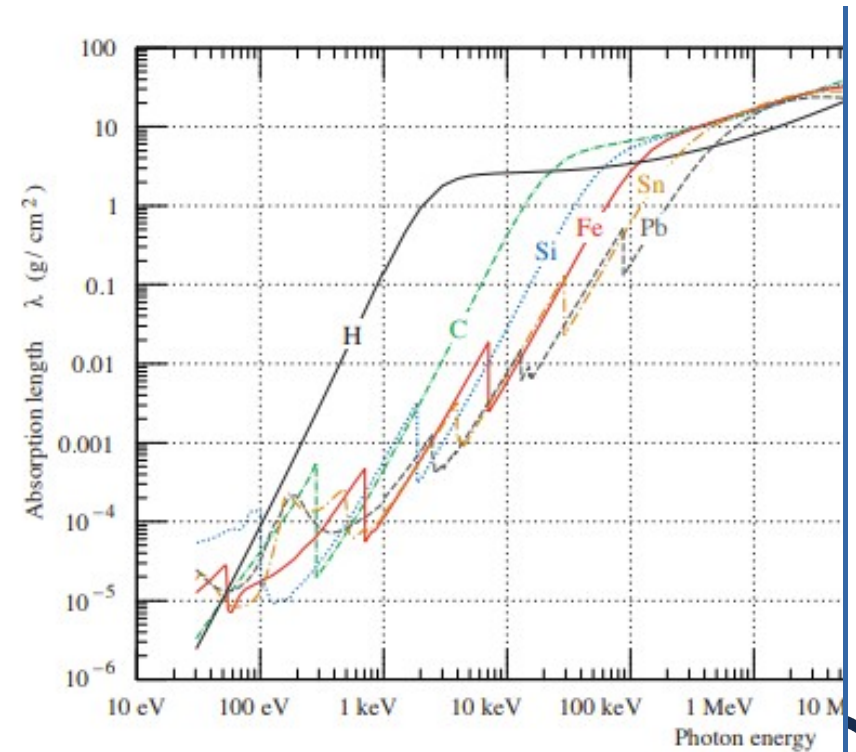


$$I = I_S \left( e^{\frac{V_D}{nV_T}} - 1 \right)$$

$I_S \propto \# \text{ minority carriers}$   
 $\propto \exp(-1/T) * 1/\text{doping}$

# Gamma spectroscopy

- For spectroscopy the gamma has to be fully contained in the detector
  - Silicon density  $\sim 2.3 \text{ g/cm}^3$ 
    - Absorption length 10 cm  $\sim 1 \text{ MeV}$
  - Germanium density  $\sim 5.5 \text{ g/cm}^3$ 
    - Absorption length 5 cm  $\sim 1 \text{ MeV}$
- Typically germanium junctions are used:
  - Cryogenic temperature
    - limit the leakage current
    - Increase the carrier lifetime
  - High purity germanium is required



## Radiation Detectors

### ▼ High Purity Germanium (HPGe) Radiation Detectors

▶ HPGe Radiation Detector Types and How to Choose

▶ HPGe Radiation Detector Cooling

HPGe Radiation Detector Electronics

HPGe Radiation Detector Options and Accessories

HPGe Radiation Detector Stock List

▶ Silicon Charged Particle Radiation Detectors

▶ Scintillation Radiation Detectors

Exempt Quantity Radioactive Sources

### High Purity Germanium (HPGe) Radiation Detectors

Semiconductor based photon radiation detectors have been evolving for over half a century, with ORTEC pioneering commercial availability for a majority of that time. Initial offerings were based around lithium-drifted germanium Ge(Li) and lithium-drifted silicon Si(Li). Ge(Li) was later replaced with more advanced, high purity germanium (HPGe) detectors. ORTEC provides a comprehensive suite of [HPGe detector solutions](#) covering an extensive range of energies and for a variety of applications.



Cryogenic cooling is required for germanium semiconductor radiation detectors. In order to support various counting geometries, ORTEC offers a [wide range of cooling options](#) ranging from standard LN<sub>2</sub> systems, to advanced electro-mechanical cryocoolers such as the [ICS™](#).



# Detector response

$$\sigma = \sqrt{a + bN + cN^2}$$

- $a$  ← electronic noise
- $b$  ← Fano factor →  $\sigma/N = \sqrt{a/N^2 + b/N + c}$
- $c$  ← disuniformities (in gain, field, ...)
- In poissonian approximation  $a=c=0$ ,  $b=1$



# detectors

	Gap [eV]	ev/couple	Fano
Si	1.12	3.86	0.115
Ge	0.67	2.96	0.12
SiC	2.5-3.5	7.6	0.04

- How many couples for 30 keV x-ray in Ge?



# detectors

	Gap [eV]	ev/couple	Fano
Si	1.12	3.86	0.115
Ge	0.67	2.96	0.12
SiC	2.5-3.5	7.6	0.04

- How many couples for 30 keV x-ray in Ge?
  - $30 \text{ keV} / 3 \text{ eV} = 10000 \text{ e/h}$
- Energy resolution?



# detectors

	Gap [eV]	ev/couple	Fano
Si	1.12	3.86	0.115
Ge	0.67	2.96	0.12
SiC	2.5-3.5	7.6	0.04

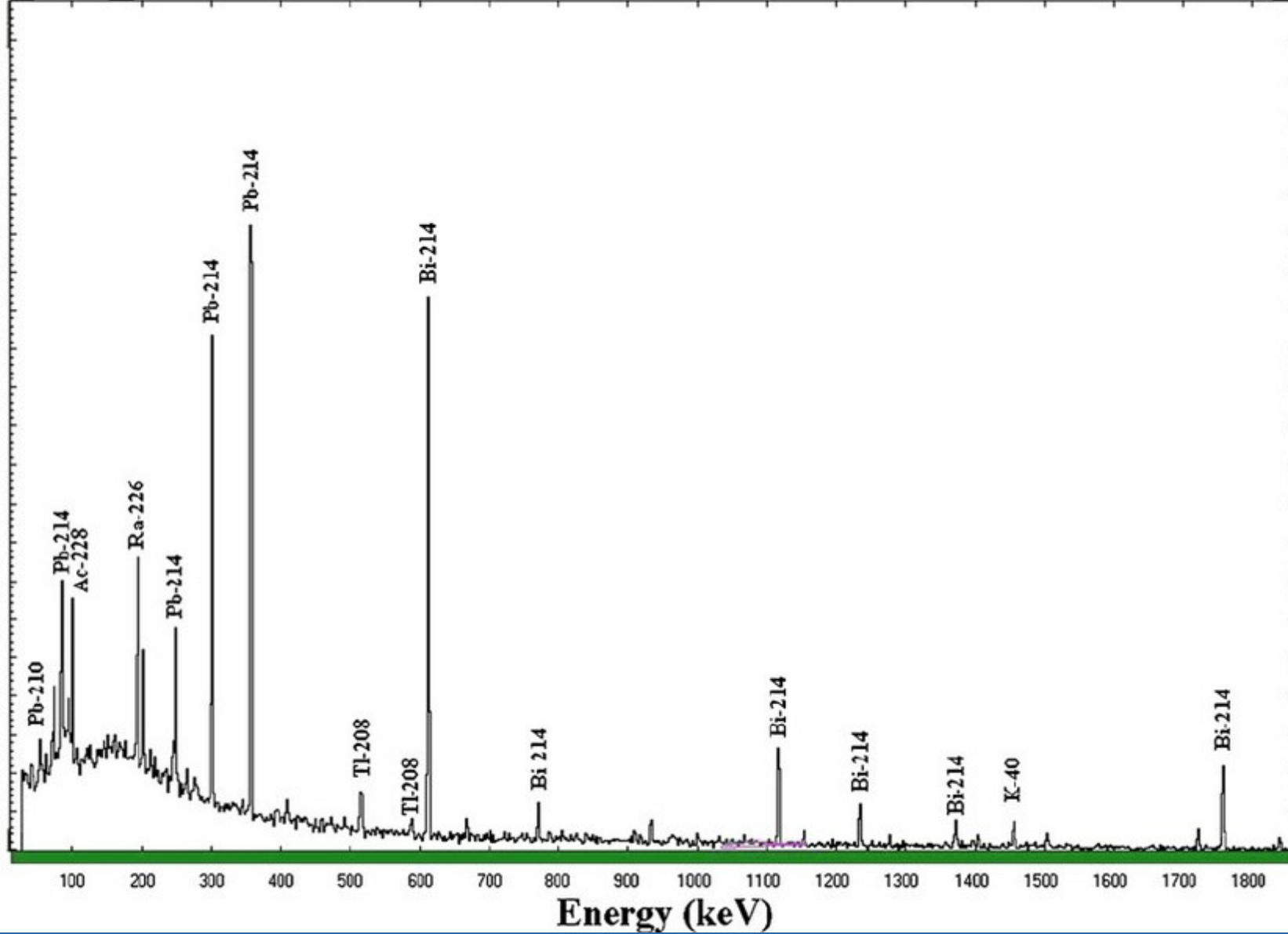
- How many couples for 30 keV x-ray in Ge?
  - $30 \text{ keV} / 3 \text{ eV} = 10000 \text{ e/h}$
- Energy resolution?
  - $2.355 * \text{sqrt}(0.12 / 10000) = 0.8 \%$







Counts



# And Silicon?

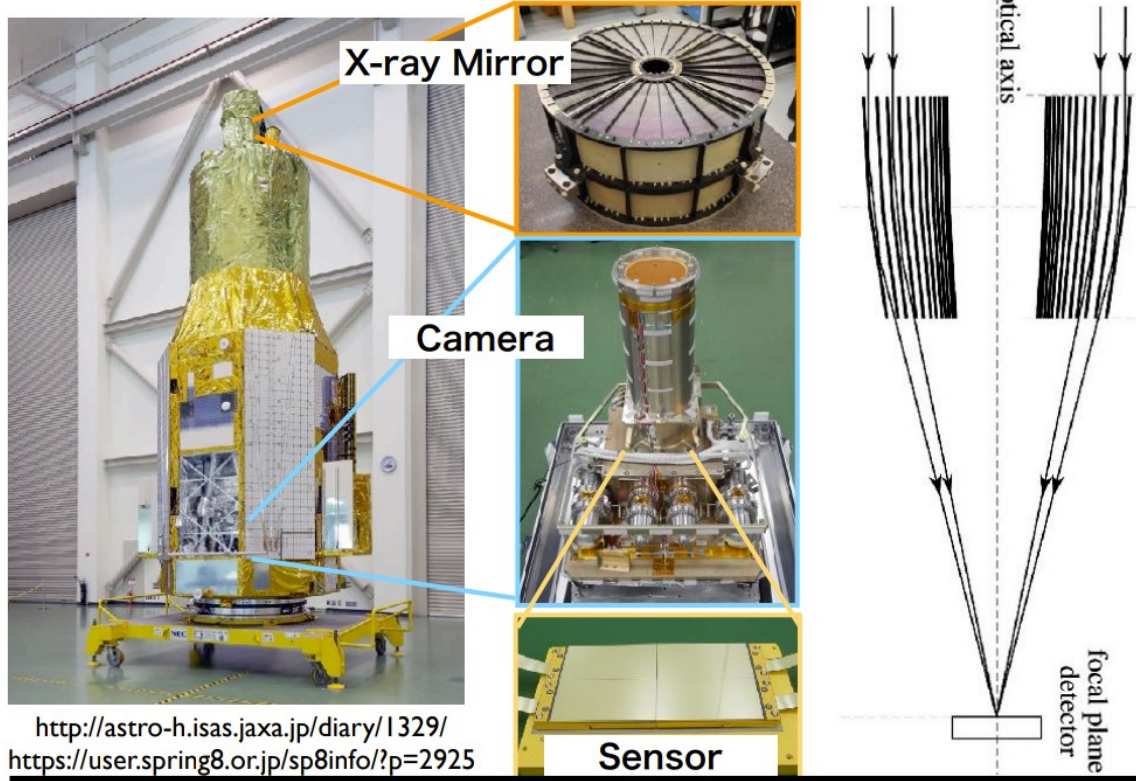
- Silicon is used for almost everything else
  - Alpha detectors
  - X-ray detectors
  - Pixel and strip detectors
- Silicon requires no cooling
  - $I_{\text{gen}} \sim O(\text{nA} / \text{cm}^2) @ 300 \text{ K}$



# X-ray imaging

## X-ray Imaging System

6



<http://astro-h.isas.jaxa.jp/diary/1329/>  
<https://user.spring8.or.jp/sp8info/?p=2925>

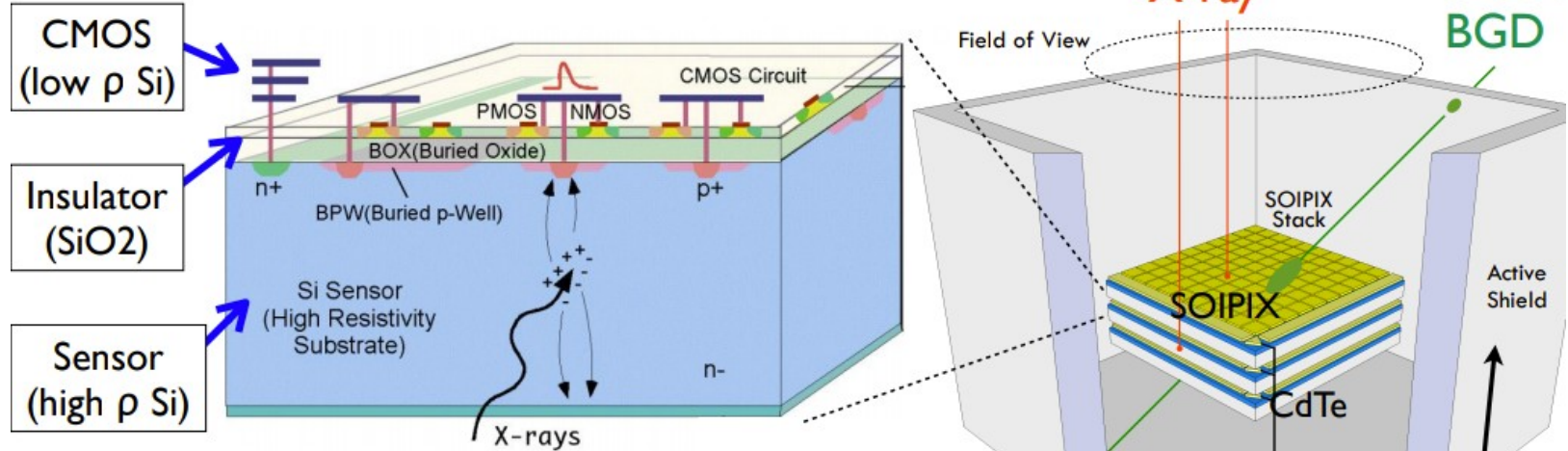
X-ray CCDs as Standard Imaging Spectrometers at 0.3–10keV.

<https://tinyurl.com/ydkarju5>



# Integrated sensor

## “XRPIX” = SOI pixel sensor for X-ray Astronomy <sup>9</sup>



Each pixel has its own trigger logic and analogue readout CMOS circuit.

Anti-coincidence Shield  
by Scintillators  
Rate ~10kHz



# Target Specification of the Device

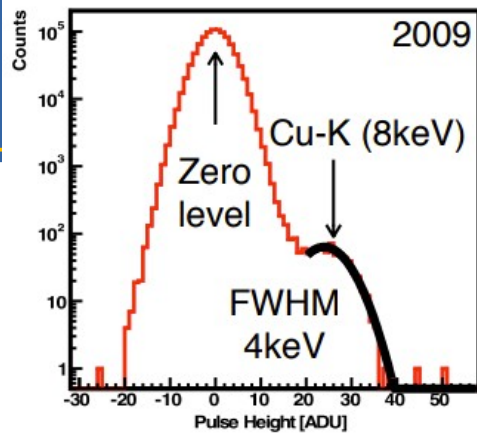
10



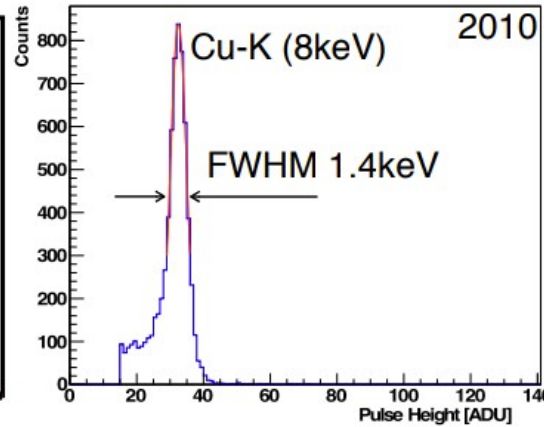
Imaging	area ~ 15x45mm <sup>2</sup> pixel ~ 30-60μm <sup>2</sup> (1" @ F=10m)	same performance as CCD
Energy Band	Req. 1-40 keV, Goal 0.5-40 keV Backside Illumination Req. <1μm, Goal 0.1μm Full Depletion Req. >250μm	
Spectroscopy	ΔE: Req. < 300eV, Goal < 140eV @ 6keV ENC: Req. <10e-, Goal < 3e- ← <b>Most Difficult</b>	
Time Resolution	< 10μsec for the anti-coincidence with the rate of ~10kHz	



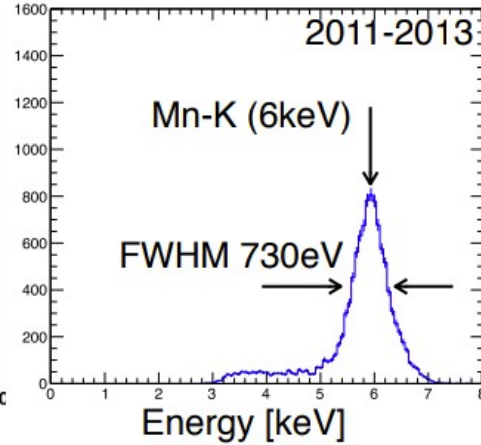
# Improvement of Spectral Performance in **Frame** Mode



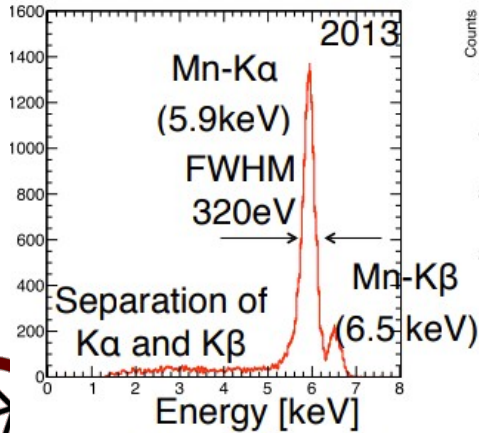
ENC ~600e (rms)



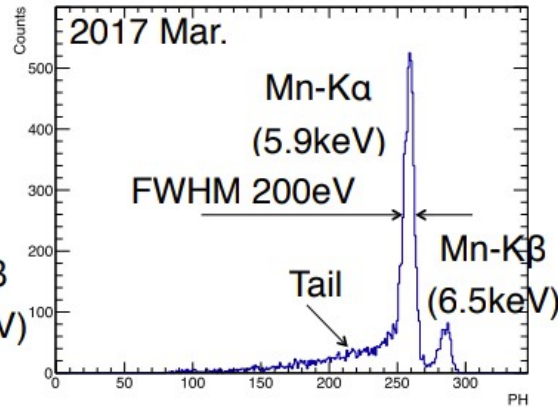
ENC ~130e (rms)



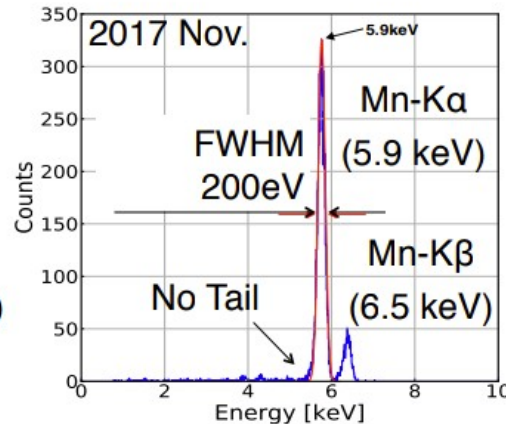
ENC ~68e (rms)



ENC ~35e (rms)



ENC ~16e (rms)

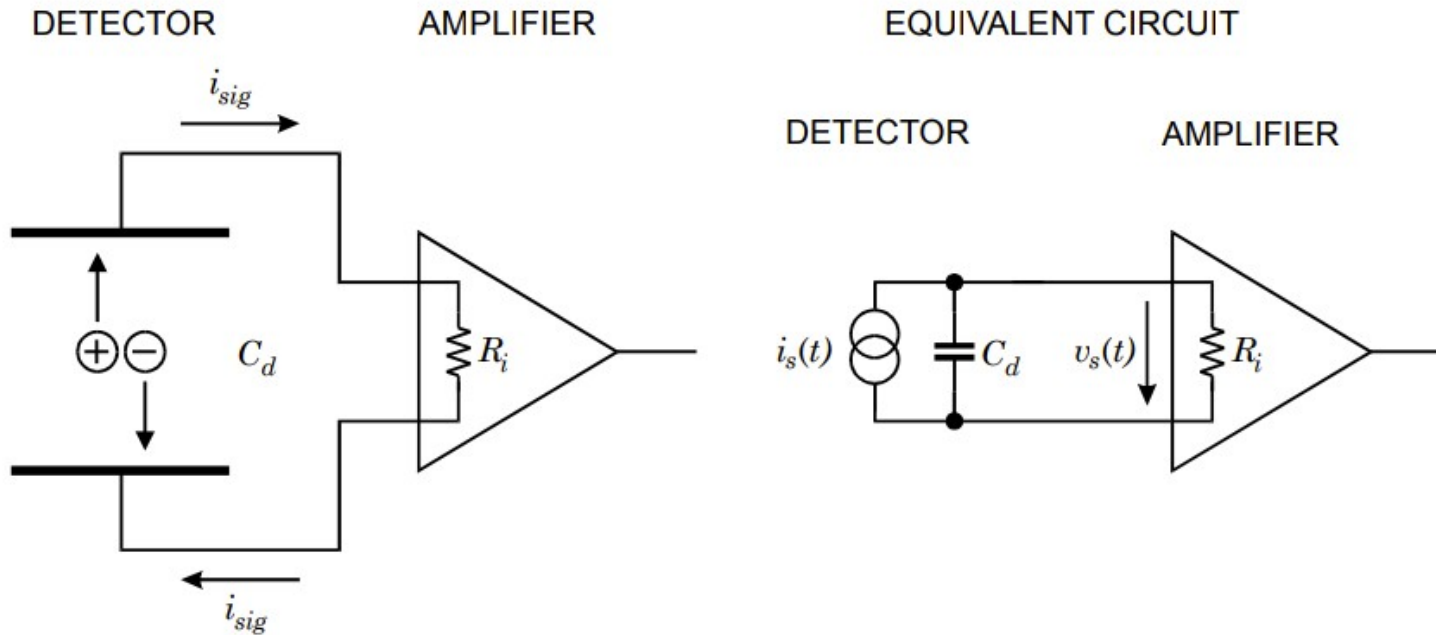


ENC ~10e (rms)

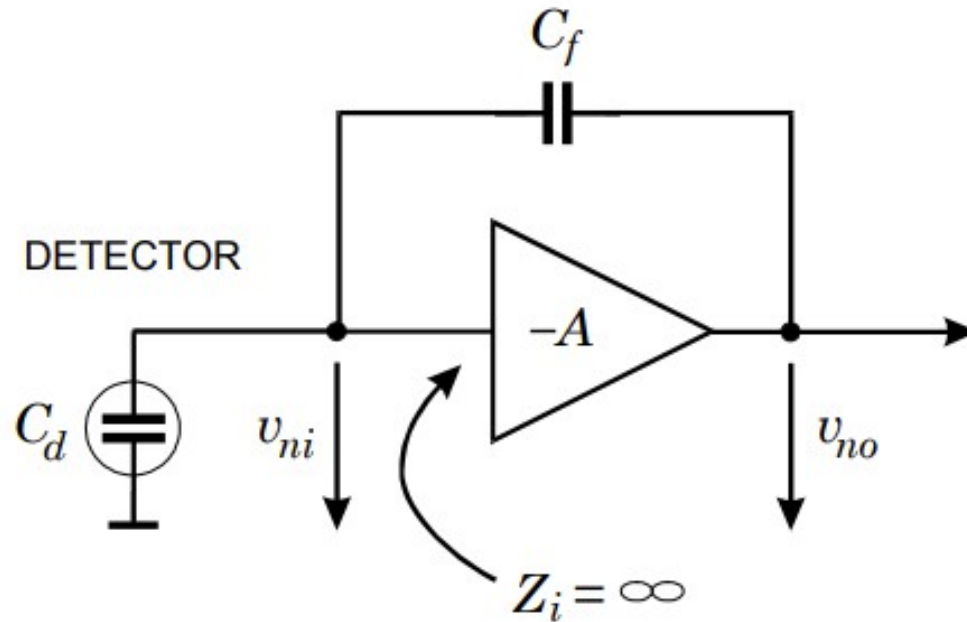
Kamehama, Kawahito+17



# Detecting pulses



# Charge[-sensitive] pre-amplifier



$$\text{Signal} = Q / C_f$$

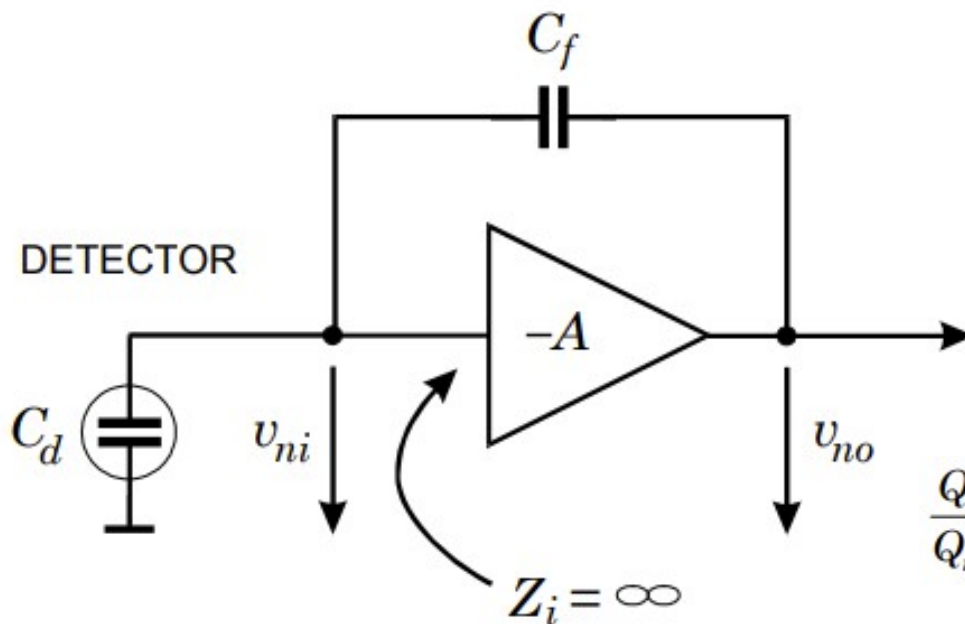
$$C_f \ll C_d$$

$$\text{Risetime} \propto C_d / (C_f \text{GBP})$$





# Charge[-sensitive] pre-amplifier



$$\text{Signal} = Q / C_f$$

$$C_f \ll C_d$$

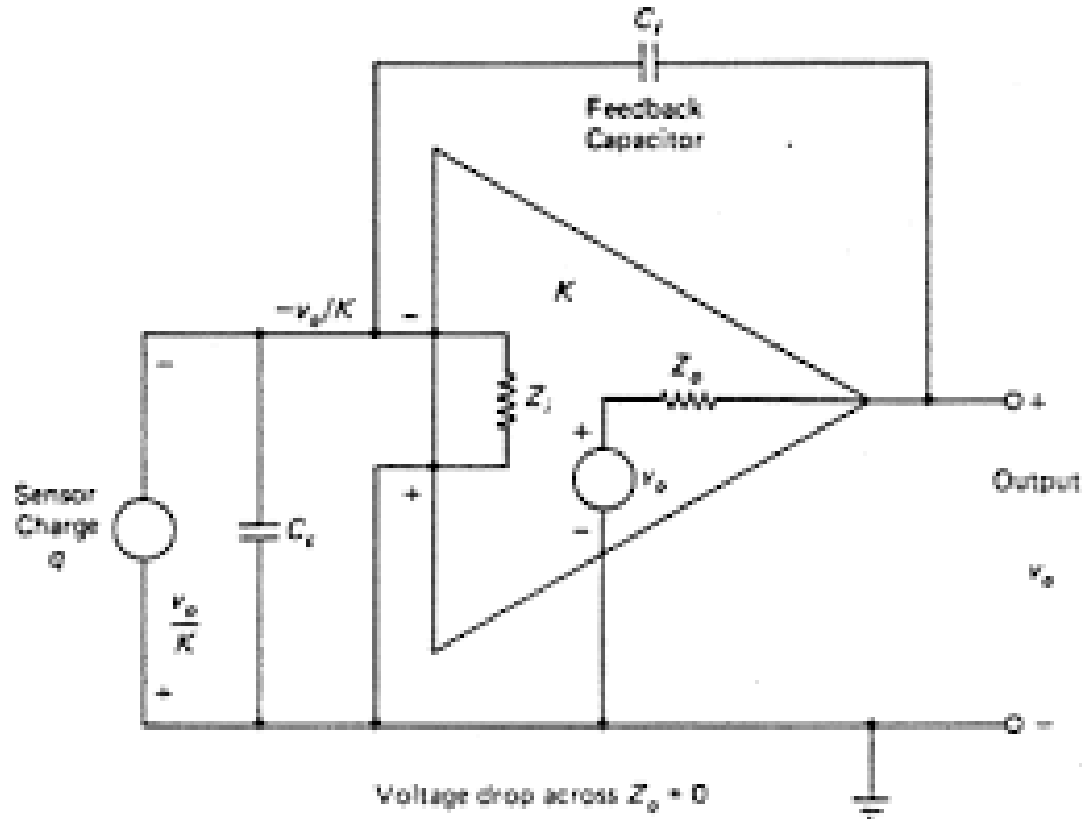
$$\text{Risetime} \propto C_d / (C_f \text{GBP})$$

SNR

$$\frac{Q_s}{Q_{ni}} = \frac{Q_s}{v_{ni}(C_d + C_f)} = \frac{1}{C} \frac{Q_s}{v_{ni}}$$

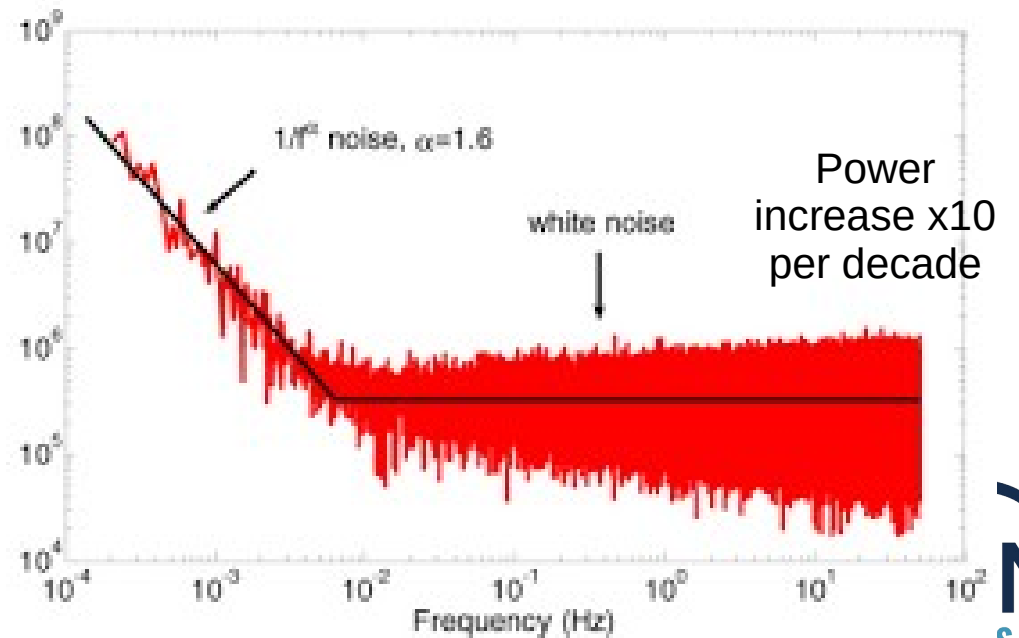


# Charge amplifier



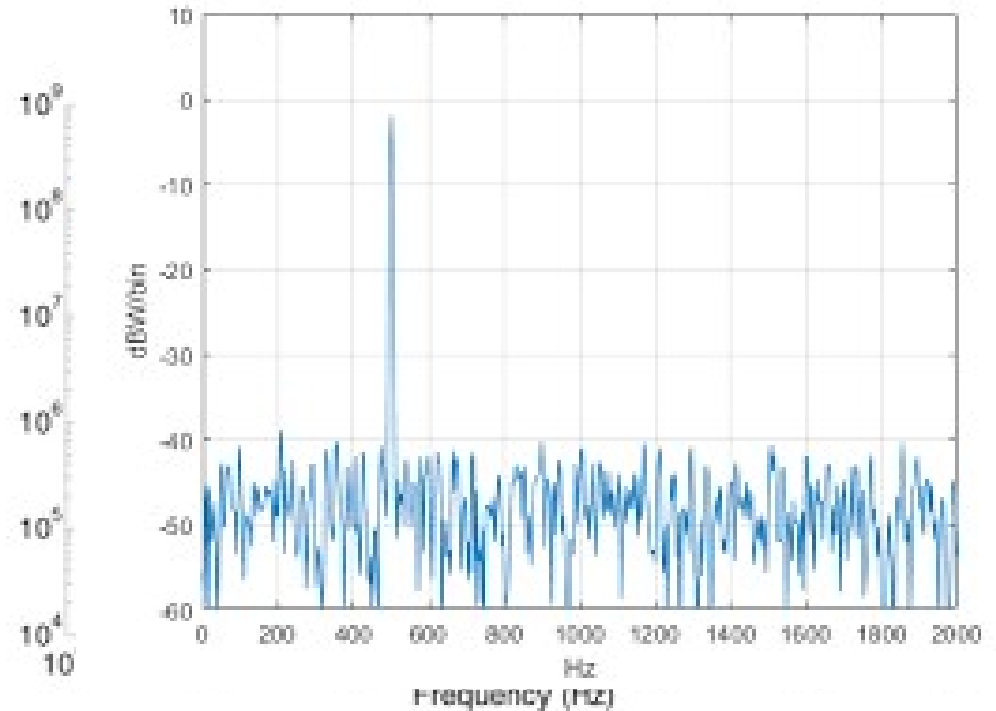
# Electronic noise

- Intrinsic
  - Thermal noise, shot noise
  - $1/f$  noise
- External
  - Pick-up
  - Ground loops

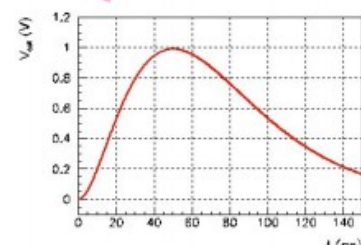
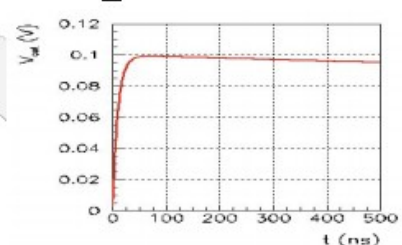
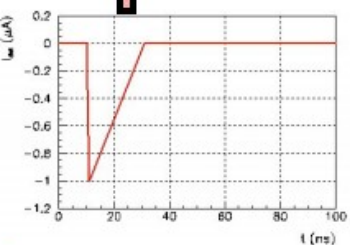
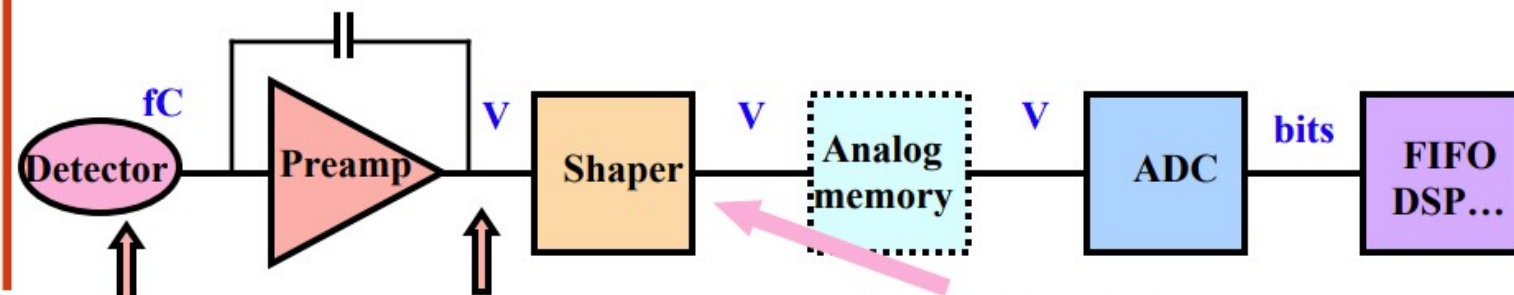


# Electronic noise

- Intrinsic
  - Thermal noise, shot noise
  - $1/f$  noise
- External
  - Pick-up
  - Ground loops



- Most front-ends follow a similar architecture



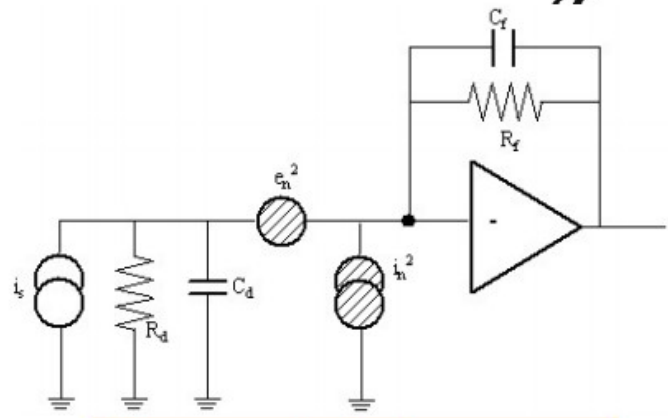
- Very small signals (fC) -> need **amplification**
- Measurement of **amplitude** and/or **time** (ADCs, discris, TDCs)
- Several thousands to millions of channels

<https://tinyurl.com/yflynbe7>

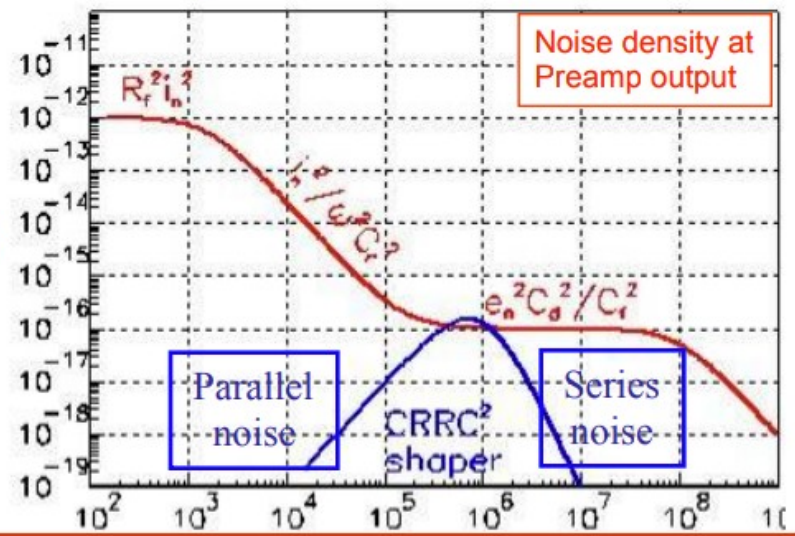
# Noise in charge pre-amplifiers



- 2 noise generators at the input
  - Parallel noise : ( $i_n^2$ ) (leakage currents)
  - Series noise : ( $e_n^2$ ) (preamp)
- Output noise spectral density :
  - $S_v(\omega) = (i_n^2 + e_n^2/|Z_d|^2) / \omega^2 C_f^2$   
 $= i_n^2 / \omega^2 C_f^2 + e_n^2 C_d^2 / C_f^2$
  - Parallel noise in  $1/\omega^2$
  - Series noise is flat, with a « noise gain » of  $C_d/C_f$
- rms noise  $V_n$ 
  - $V_n^2 = \int S_v(\omega) d\omega / 2\pi \rightarrow \infty (!)$
  - Benefit of shaping...



Noise generators in charge preamp



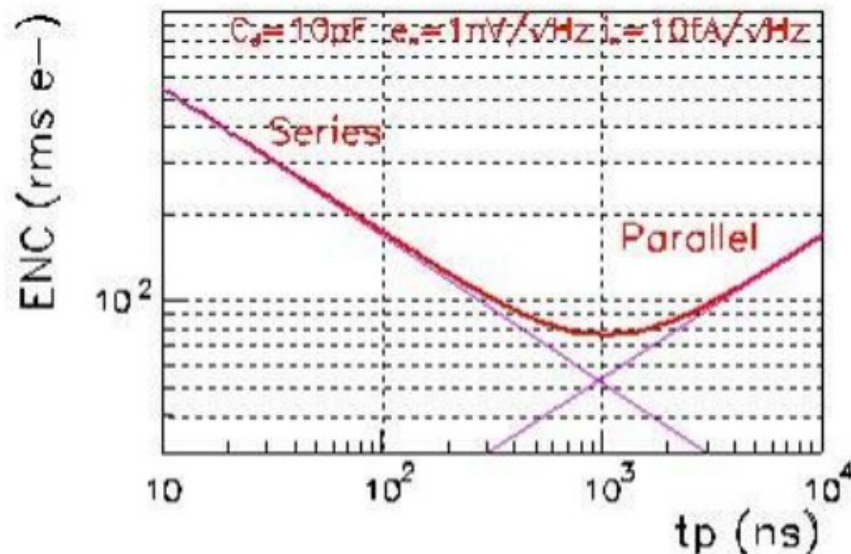
- A useful formula : **ENC (e<sup>-</sup> rms) after a CRRC<sup>2</sup> shaper :**

$$\text{ENC} = 174 e_n C_{\text{tot}} / \sqrt{t_p} (\delta) \oplus 166 i_n \sqrt{t_p} (\delta)$$

- $e_n$  in nV/  $\sqrt{\text{Hz}}$ ,  $i_n$  in pA/  $\sqrt{\text{Hz}}$  are the **preamp** noise spectral densities
- $C_{\text{tot}}$  (in pF) is dominated by the detector ( $C_d$ ) + input preamp capacitance ( $C_{\text{PA}}$ )
- $t_p$  (in ns) is the shaper peaking time (5-100%)

## Noise minimization

- Minimize source capacitance
- Operate at optimum shaping time
- Preamp series noise ( $e_n$ ) best with high transconductance ( $g_m$ ) in input transistor  
=> large current, optimal size



# Equivalent Noise Charge (ENC) after CRRC<sup>n</sup> *Omega*

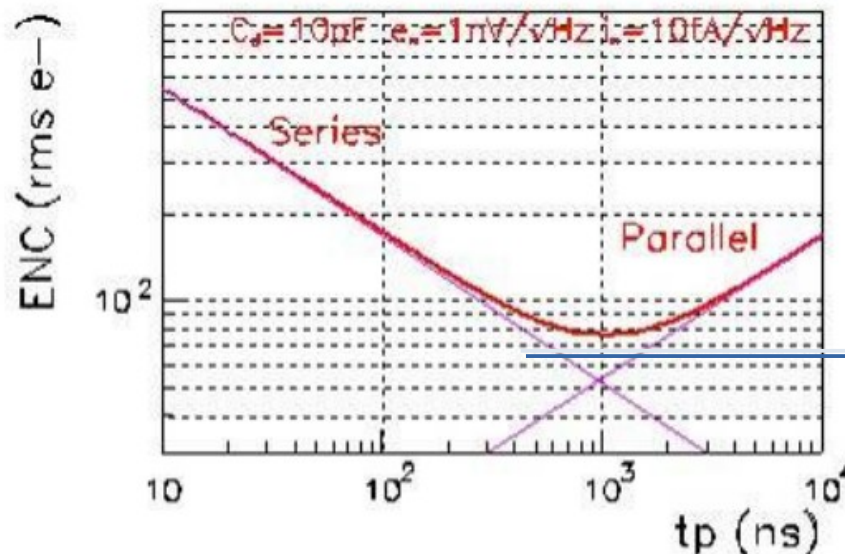
- A useful formula : **ENC (e<sup>-</sup> rms) after a CRRC<sup>2</sup> shaper :**

$$\text{ENC} = 174 e_n C_{\text{tot}} / \sqrt{t_p} (\delta) \oplus 166 i_n \sqrt{t_p} (\delta)$$

- $e_n$  in nV/√Hz,  $i_n$  in pA/√Hz are the **preamp** noise spectral densities
- $C_{\text{tot}}$  (in pF) is dominated by the detector ( $C_d$ ) + input preamp capacitance ( $C_{\text{PA}}$ )
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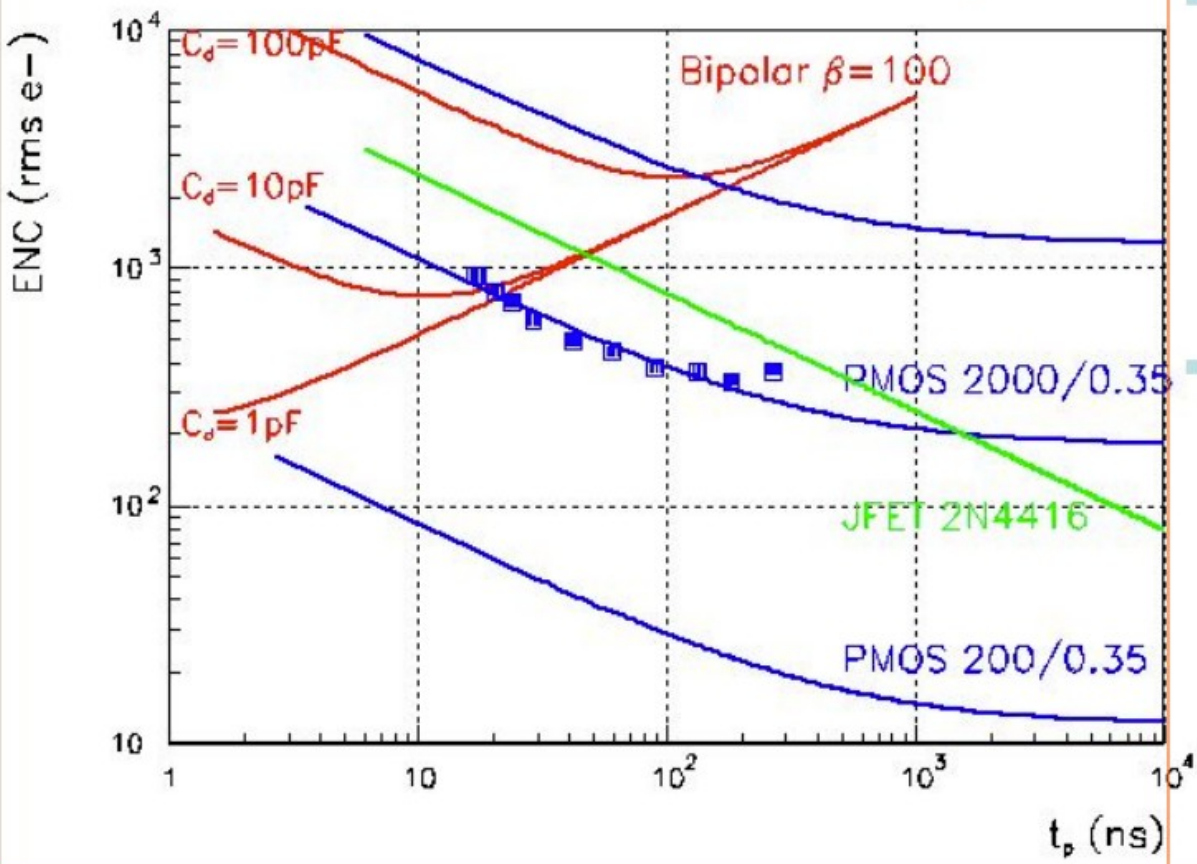
# ENC for various technologies

Omega



- ENC for  $C_d=1, 10$  and  $100$  pF at  $I_D = 500$  uA
  - MOS transistors best between  $20$  ns -  $2$   $\mu$ s

- **Parameters**
- **Bipolar :**
  - $g_m = 20$  mA/V
  - $R_{BB} = 25$   $\Omega$
  - $e_n = 1$  nV/ $\sqrt{\text{Hz}}$
  - $I_B = 5$  uA
  - $i_n = 1$  pA/ $\sqrt{\text{Hz}}$
  - $C_{PA} = 100$  fF
- **PMOS 2000/0.35**
  - $g_m = 10$  mA/V
  - $e_n = 1.4$  nV/ $\sqrt{\text{Hz}}$
  - $C_{PA} = 5$  pF
  - $1/f$  :



# ENC for various technologies

Omega

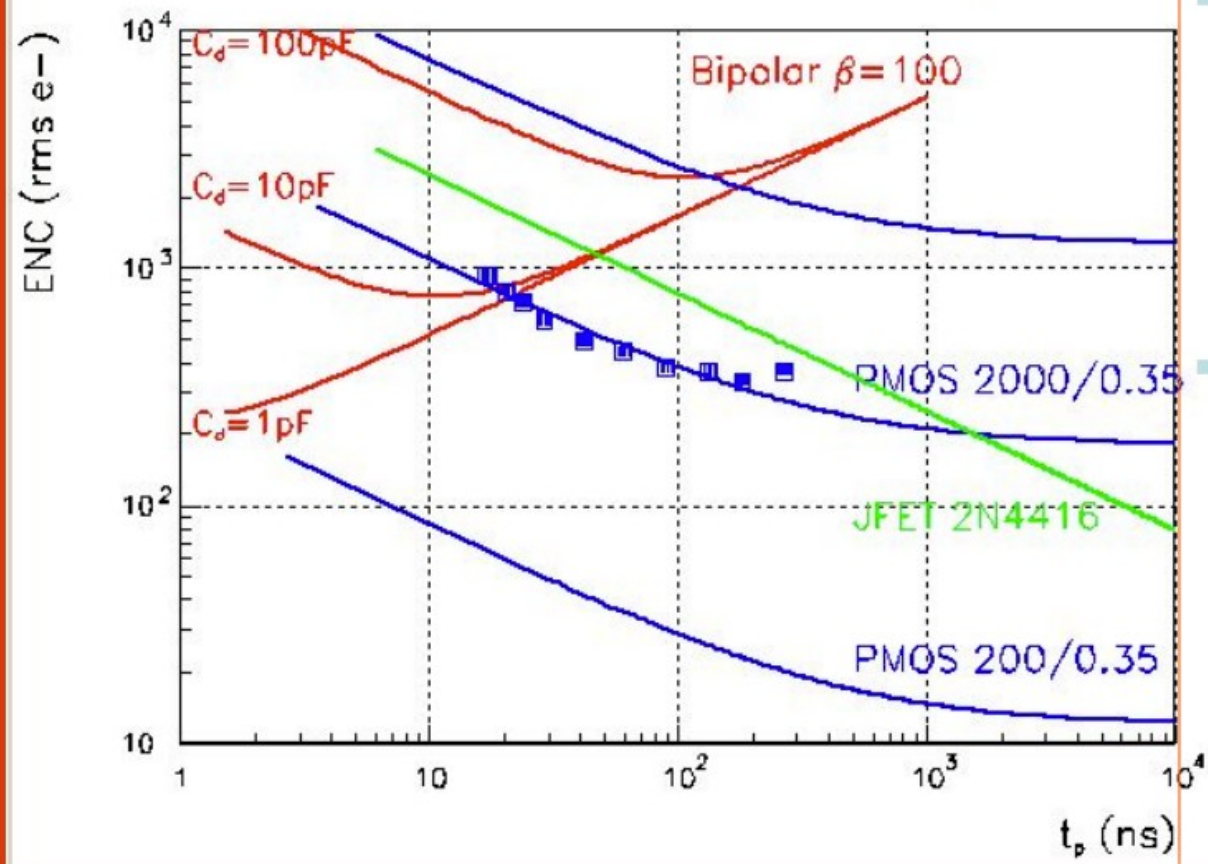


- ENC for  $C_d=1, 10$  and  $100$  pF at  $I_D = 500$  uA
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  - $e_n = 1$  nV/ $\sqrt{\text{Hz}}$
  - $I_B = 5$  uA
  - $i_c = 1$  pA/ $\sqrt{\text{Hz}}$
  - $C_{PA} = 100$  fF
- PMOS 2000/0.35**
  - $g_m = 10$  mA/V
  - $e_n = 1.4$  nV/ $\sqrt{\text{Hz}}$
  - $C_{PA} = 5$  pF
  - $1/f$  :

Shot noise

$$\sigma_i = \sqrt{2qI\Delta f}$$



# ORCA-FusionBT

CAMERA SPECS

LOW NOISE AND EXCEPTIONAL  
READOUT NOISE UNIFORMITY WITH HIGH QE



**LOW READOUT NOISE**  
0.7 electrons rms  
Ultra-quiet Scan

**HIGH QE**  
95 % @550 nm  
Gen III Back-illuminated sCMOS

**HIGH SPEED**  
89.1 fps  
@ 2304 x 2304 (16 bit)

**HIGH RESOLUTION**  
2304 × 2304  
5.3 Megapixels

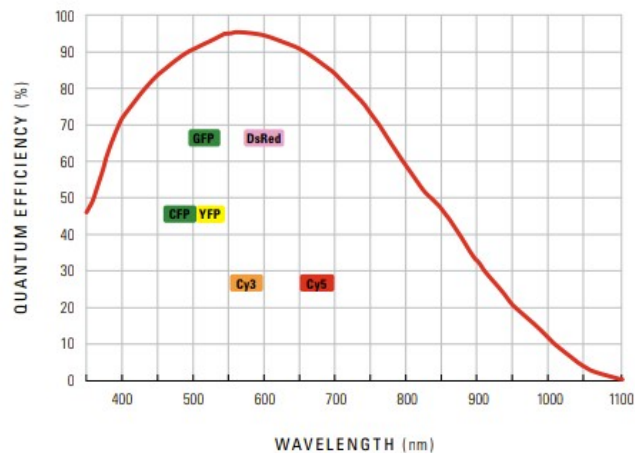
**PRNU**  
0.06 % rms  
@ 7500 electrons

**PIXEL SIZE**  
6.5 μm × 6.5 μm

**DYNAMIC RANGE**  
21 400:1  
Ultra-quiet Scan

**DSNU**  
0.06 electrons rms  
Ultra-quiet Scan

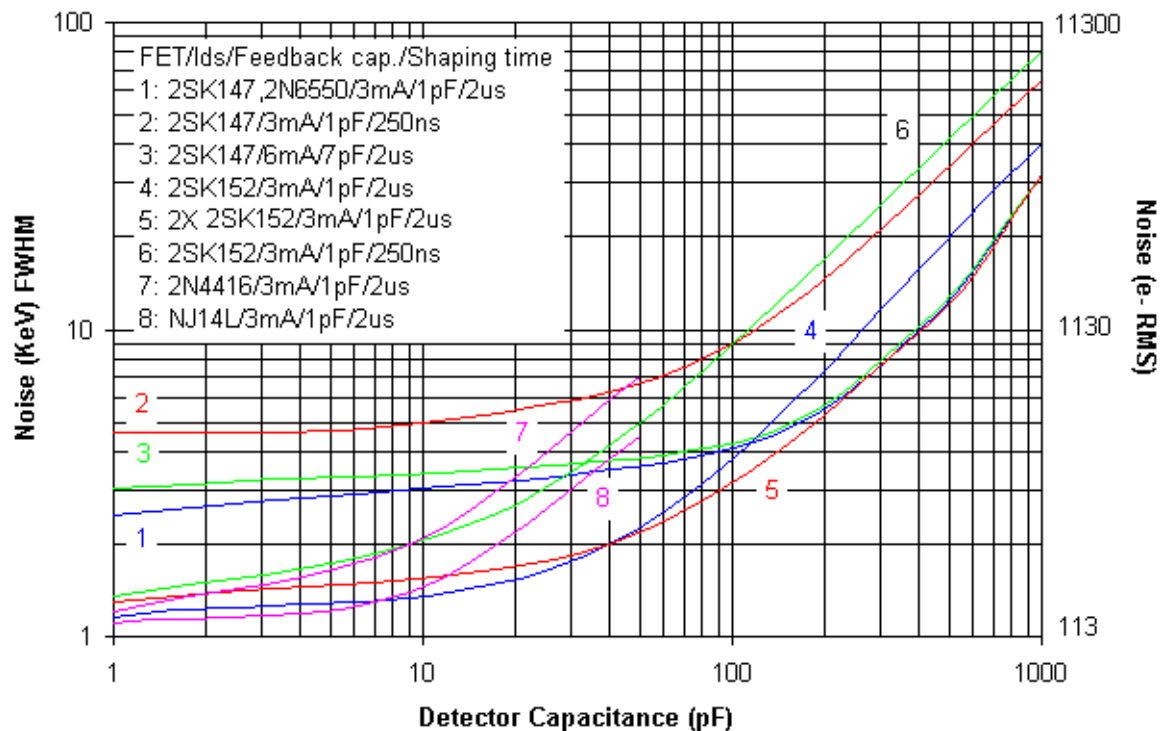
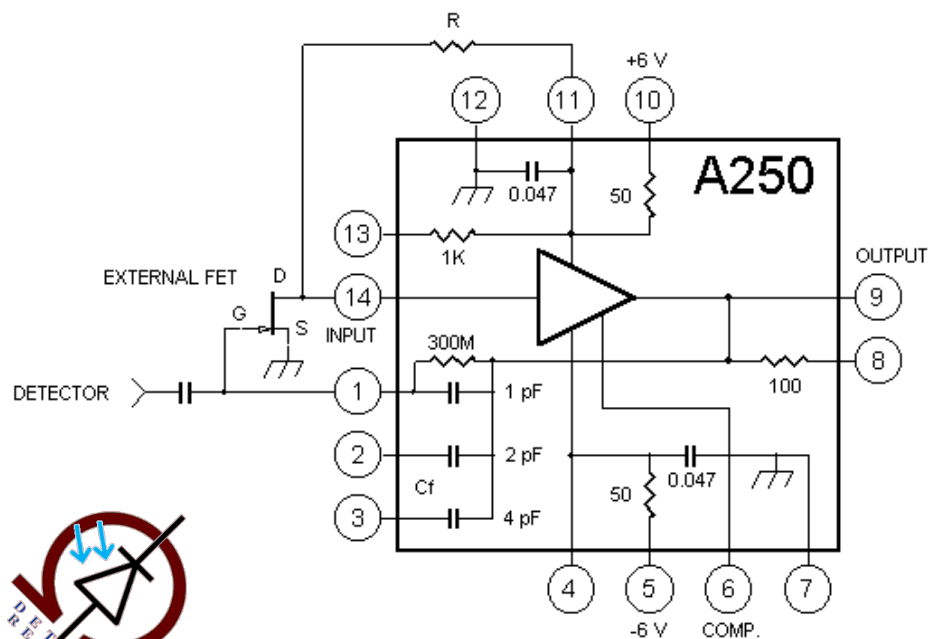
## Back-thin Boosted QE for Maximum Photon Collection



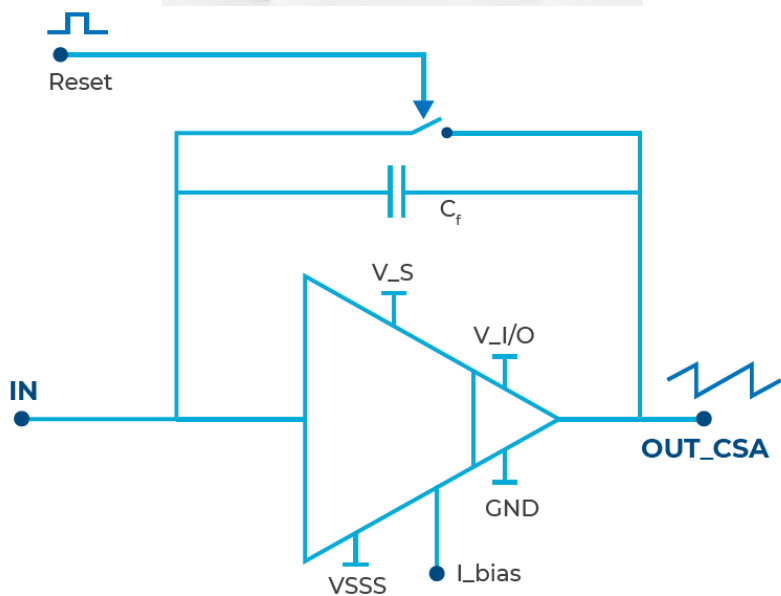
# Continuous reset Charge amplifier



<https://www.amptek.com/>



# Pulsed reset Charge amplifier

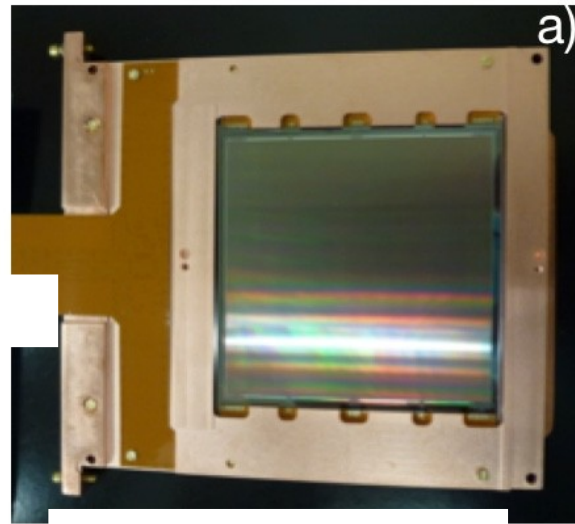
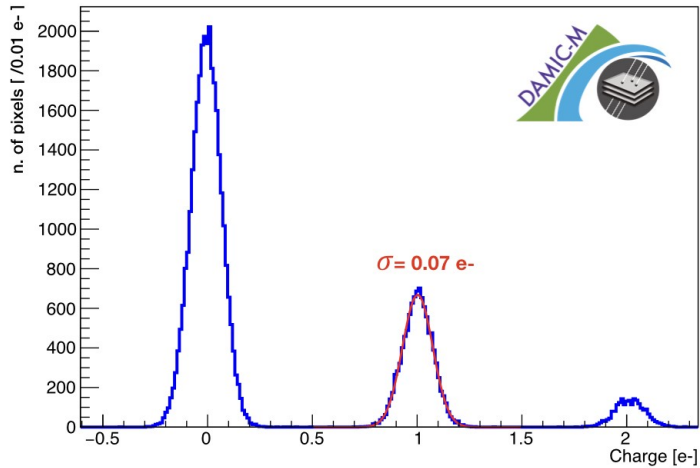


CUBE Version	Polarity	Detector capacitance [pF]	Feedback capacitance [fF]	ENC (CUBE only, 3.6 eV/e)
PRE_016	Negative (electrons)	< 0.25	25	3.3 e- @ 1 $\mu$ s
PRE_031	Negative (electrons)	< 0.5	25	3.3 e- @ 1 $\mu$ s
PRE_033	Negative (electrons)	<0.25	25	2.4e- @ 1 $\mu$ s
PRE_037	Positive (holes)	< 0.70	25	4.0e- @1 $\mu$ s
PRE_038	Positive (holes)	0.50 - 3.00	50	12.3 e- @1 $\mu$ s
PRE_039	Positive (holes)	3.00-10.00	50	20.2e- @1 $\mu$ s
PRE_040	Negative (electrons)	0.50-3.00	50	12.4e- @1 $\mu$ s
PRE_041	Both (selectable)	3.00-10.00	500	57 e- @1 $\mu$ s
PRE_042	Both (selectable)	0.50-3.00	500	35.5 e- @1 $\mu$ s

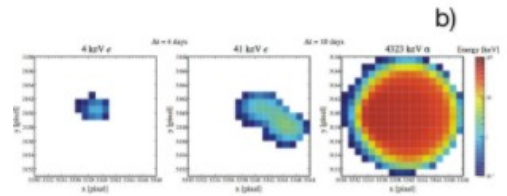
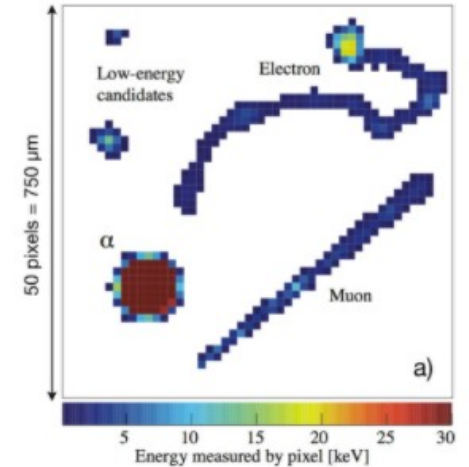
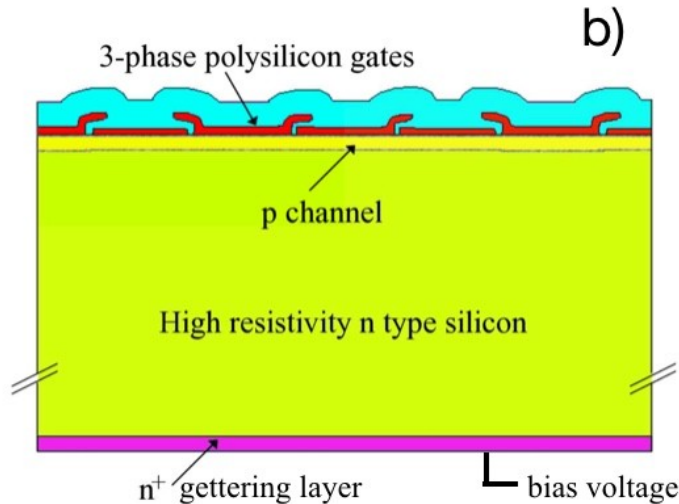


# DAMIC

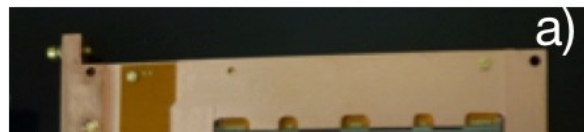
<https://damic.uchicago.edu/detector.php>



15 x 15 x 500 um pixel  
Fully depleted



# DAMIC



<https://damic.uchicago.edu/>

